



US010622340B2

(12) **United States Patent**
Jeong et al.

(10) **Patent No.:** **US 10,622,340 B2**

(45) **Date of Patent:** **Apr. 14, 2020**

(54) **SEMICONDUCTOR PACKAGE**

(71) Applicant: **SAMSUNG ELECTRONICS CO., LTD.**, Suwon-si, Gyeonggi-Do (KR)

(72) Inventors: **Chanhee Jeong**, Chungcheongnam-Do (KR); **Hyunki Kim**, Chungcheongnam-Do (KR); **Junwoo Park**, Suwon-si (KR); **Byoung Wook Jang**, Chungcheongnam-Do (KR); **Sunchul Kim**, Chungcheongnam-Do (KR); **Su-Min Park**, Suwon-si (KR); **Pyoungwan Kim**, Suwon-si (KR); **Inku Kang**, Hwaseong-si (KR); **Heeyeol Kim**, Chungcheongnam-Do (KR)

(73) Assignee: **Samsung Electronics Co., Ltd.**, Suwon-si, Gyeonggi-do (KR)

(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 0 days.

(21) Appl. No.: **15/818,346**

(22) Filed: **Nov. 20, 2017**

(65) **Prior Publication Data**

US 2018/0145061 A1 May 24, 2018

(30) **Foreign Application Priority Data**

Nov. 21, 2016 (KR) 10-2016-0155195
Apr. 20, 2017 (KR) 10-2017-0051203

(51) **Int. Cl.**

H01L 25/10 (2006.01)
H01L 21/48 (2006.01)

(Continued)

(52) **U.S. Cl.**

CPC **H01L 25/105** (2013.01); **H01L 21/4853** (2013.01); **H01L 21/4857** (2013.01);
(Continued)

(58) **Field of Classification Search**

CPC . H01L 21/56; H01L 23/3121; H01L 23/3128; H01L 23/3157; H01L 23/481; H01L 2924/1815; H01L 2924/183; H01L 25/105; H01L 24/97; H01L 23/5389; H01L 2225/1041; H01L 21/565
See application file for complete search history.

(56)

References Cited

U.S. PATENT DOCUMENTS

6,329,610 B1 * 12/2001 Takubo H01L 23/49827 174/264
7,608,921 B2 10/2009 Pendse
(Continued)

OTHER PUBLICATIONS

Li et al., "An Improvement of Thermal Conductivity of Underfill Materials for Flip-Chip Packages", IEEE Transactions on Advanced Packaging, vol. 26, No. 1, Feb. 2003. pp. 25-32. (Year: 2003).*

Primary Examiner — Vincent Wall

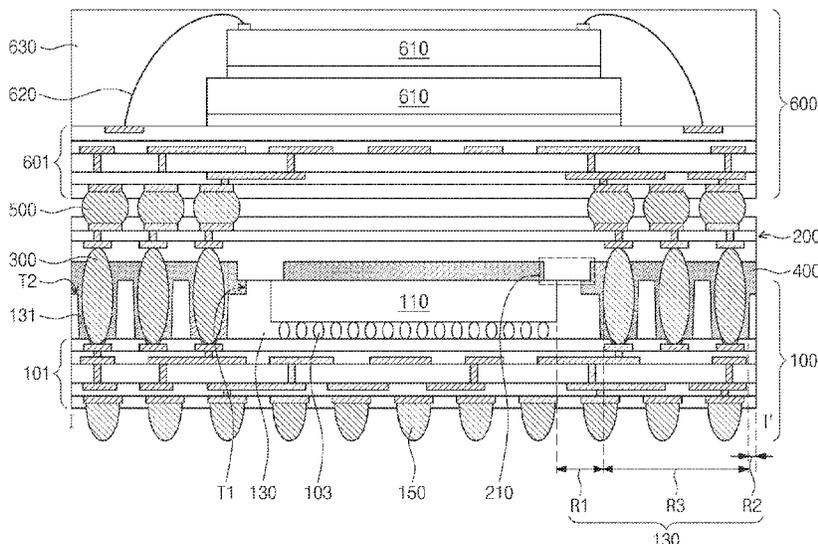
(74) *Attorney, Agent, or Firm* — Volentine, Whitt & Francos, PLLC

(57)

ABSTRACT

A semiconductor package includes a semiconductor chip disposed on a first substrate, a mold layer covering a sidewall of the semiconductor chip and including a through-hole, a second substrate disposed on the semiconductor chip, a connection terminal disposed between the first substrate and the second substrate and provided in the through-hole, and an underfill resin layer extending from between the semiconductor chip and the second substrate into the through-hole.

18 Claims, 19 Drawing Sheets



(51)	Int. Cl. <i>H01L 21/56</i> (2006.01) <i>H01L 23/31</i> (2006.01) <i>H01L 23/538</i> (2006.01) <i>H01L 23/00</i> (2006.01) <i>H01L 25/00</i> (2006.01) <i>H01L 23/498</i> (2006.01)	9,269,648 B2 * 2/2016 Higgins H01L 21/565 9,502,342 B2 11/2016 Kim 9,741,630 B2 * 8/2017 Ko H01L 24/48 2008/0169546 A1 * 7/2008 Kwon H01L 21/561 257/686 2009/0174081 A1 * 7/2009 Furuta H01L 23/49838 257/777 2010/0072598 A1 * 3/2010 Oh H01L 25/105 257/686
(52)	U.S. Cl. CPC <i>H01L 21/565</i> (2013.01); <i>H01L 23/3121</i> (2013.01); <i>H01L 23/3128</i> (2013.01); <i>H01L 23/3135</i> (2013.01); <i>H01L 23/5383</i> (2013.01); <i>H01L 23/5385</i> (2013.01); <i>H01L 24/19</i> (2013.01); <i>H01L 24/20</i> (2013.01); <i>H01L 24/97</i> (2013.01); <i>H01L 25/50</i> (2013.01); <i>H01L 23/49811</i> (2013.01); <i>H01L 23/49816</i> (2013.01); <i>H01L 23/5386</i> (2013.01); <i>H01L 23/5389</i> (2013.01); <i>H01L 24/13</i> (2013.01); <i>H01L 24/32</i> (2013.01); <i>H01L 24/48</i> (2013.01); <i>H01L 2224/04042</i> (2013.01); <i>H01L 2224/13101</i> (2013.01); <i>H01L 2224/16225</i> (2013.01); <i>H01L 2224/214</i> (2013.01); <i>H01L 2224/32145</i> (2013.01); <i>H01L 2224/32225</i> (2013.01); <i>H01L 2224/48091</i> (2013.01); <i>H01L 2224/48227</i> (2013.01); <i>H01L 2224/73265</i> (2013.01); <i>H01L 2224/97</i> (2013.01); <i>H01L 2225/0651</i> (2013.01); <i>H01L 2225/06568</i> (2013.01); <i>H01L 2225/1023</i> (2013.01); <i>H01L 2225/1035</i> (2013.01); <i>H01L 2225/1041</i> (2013.01); <i>H01L 2225/1058</i> (2013.01); <i>H01L 2924/00014</i> (2013.01); <i>H01L 2924/15151</i> (2013.01); <i>H01L 2924/15311</i> (2013.01)	2010/0330742 A1 * 12/2010 Sugiyama H01L 23/49833 438/107 2012/0049348 A1 * 3/2012 Ro H01L 23/49811 257/737 2013/0187288 A1 * 7/2013 Hong H01L 25/105 257/774 2014/0035137 A1 * 2/2014 Kwon H01L 23/49838 257/738 2014/0048906 A1 * 2/2014 Shim H01L 23/481 257/531 2014/0070396 A1 * 3/2014 Kyoizuka H01L 24/19 257/698 2014/0124910 A1 * 5/2014 Lee H01L 24/33 257/668 2014/0210109 A1 * 7/2014 Tanaka H01L 23/145 257/778 2014/0252646 A1 * 9/2014 Hung H01L 23/481 257/774 2014/0264839 A1 * 9/2014 Tsai H01L 23/49816 257/737 2014/0291830 A1 * 10/2014 Hwang H01L 25/07 257/686 2014/0327129 A1 * 11/2014 Cho H01L 23/552 257/713 2014/0339708 A1 * 11/2014 Jang H01L 23/34 257/777 2015/0115467 A1 * 4/2015 Park H01L 23/3128 257/774 2016/0056103 A1 * 2/2016 Kim H01L 25/074 257/774
(56)	References Cited U.S. PATENT DOCUMENTS 8,159,061 B2 * 4/2012 Kawabata H01L 25/0652 257/686 8,736,033 B1 * 5/2014 Chuo H01L 23/552 257/659	2016/0307778 A1 * 10/2016 Lin H01L 24/19 2017/0178992 A1 * 6/2017 Jeong H01L 23/3157 2017/0358535 A1 * 12/2017 Yoo H01L 21/4853 2018/0145061 A1 * 5/2018 Jeong H01L 25/50

* cited by examiner

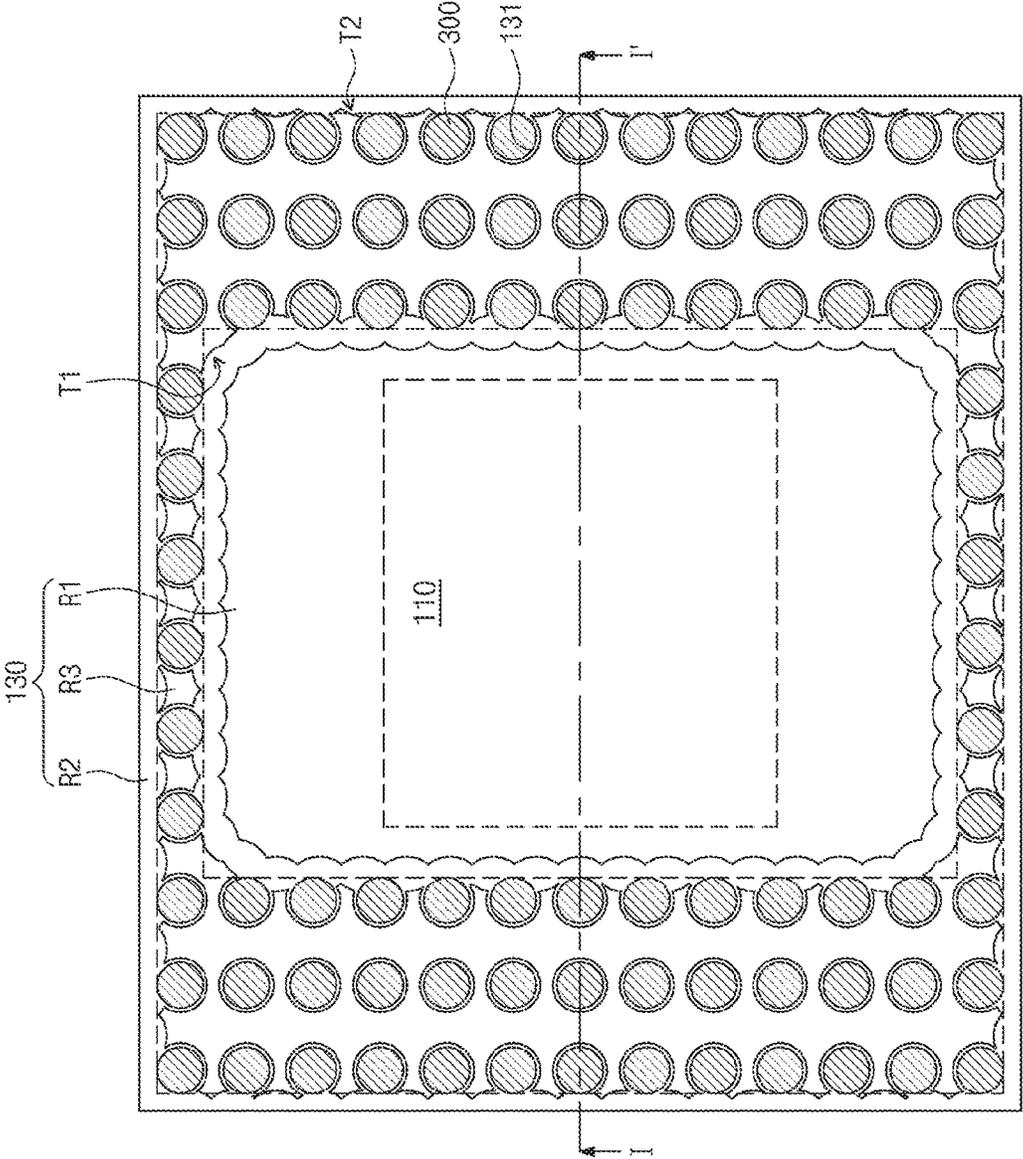
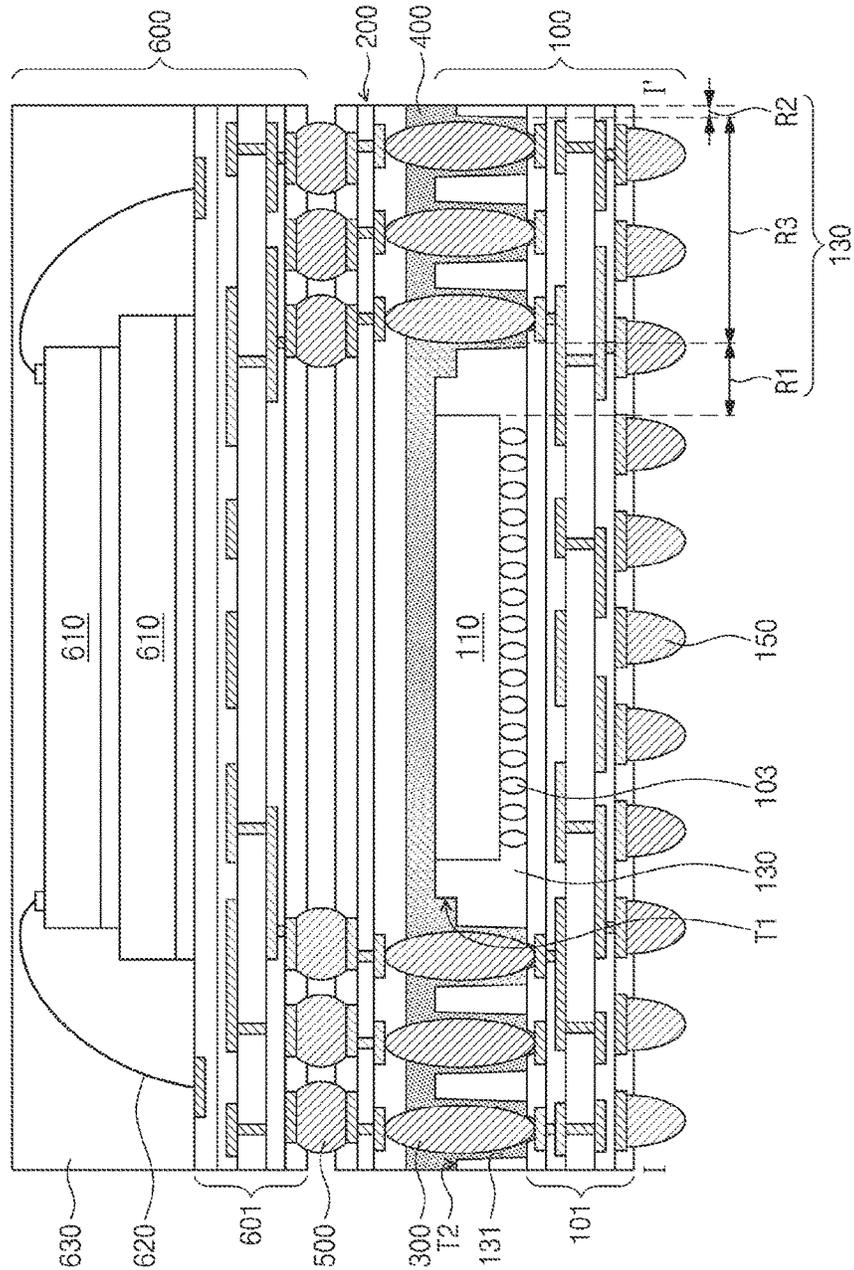


FIG. 2A

FIG. 2B



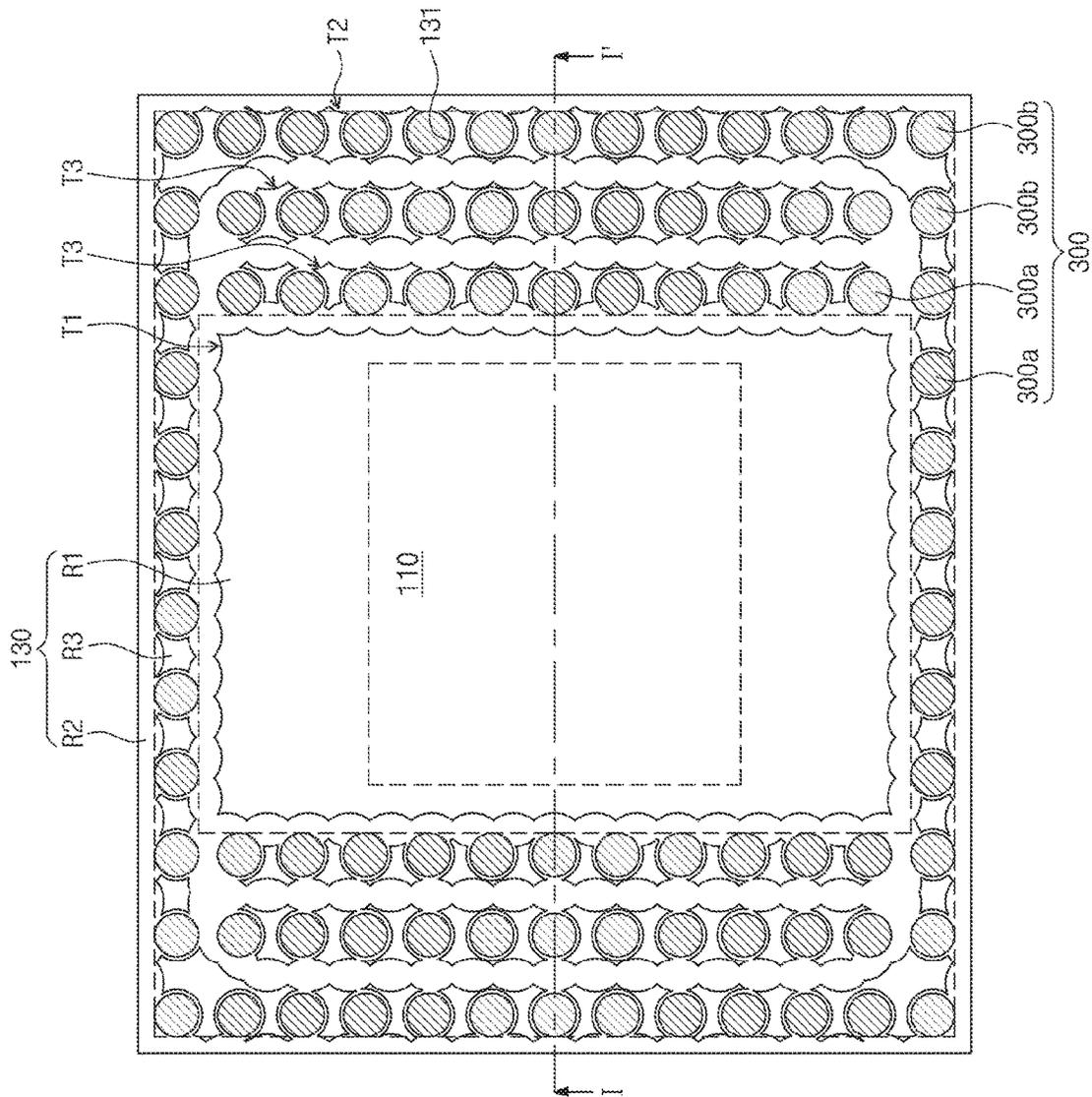
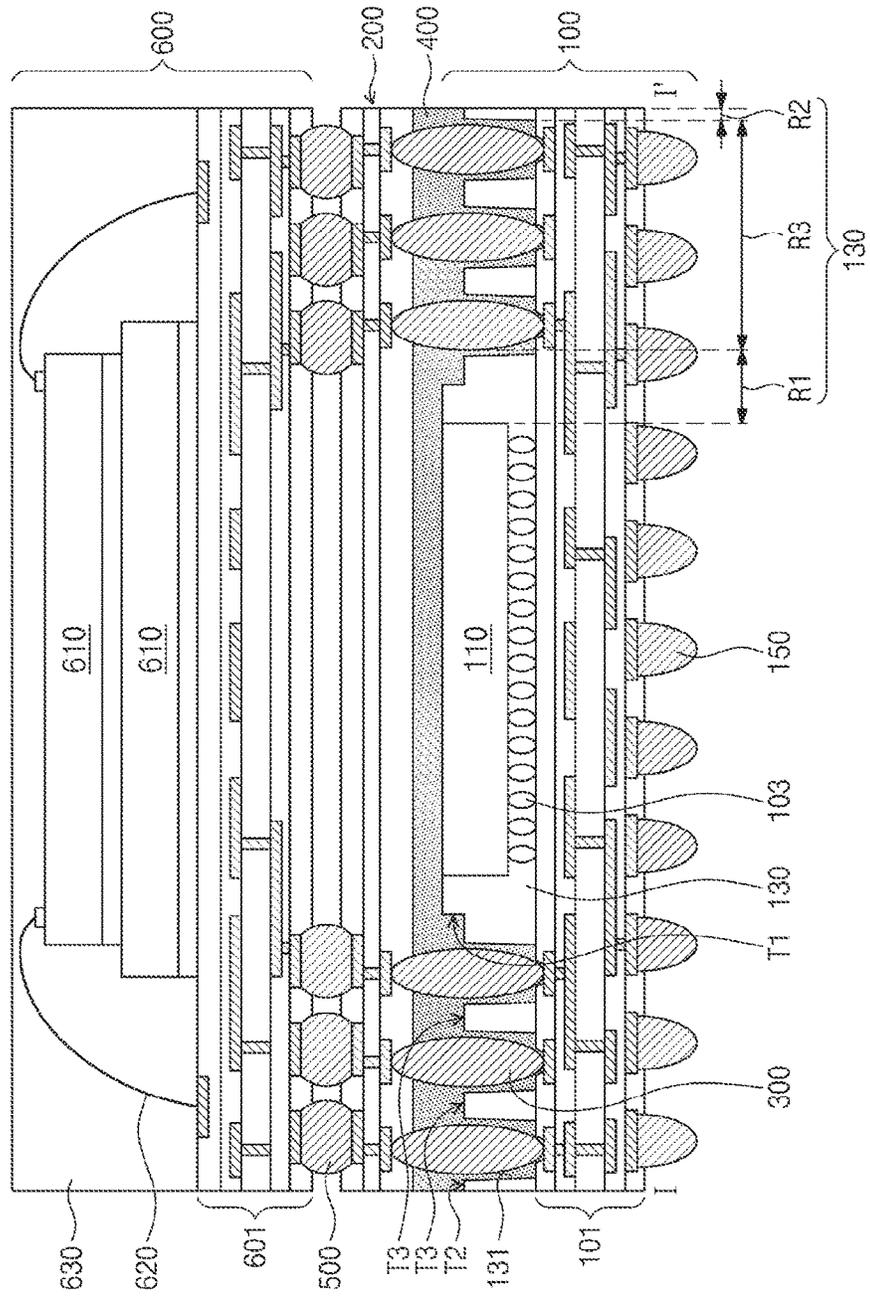


FIG. 3A

FIG. 3B



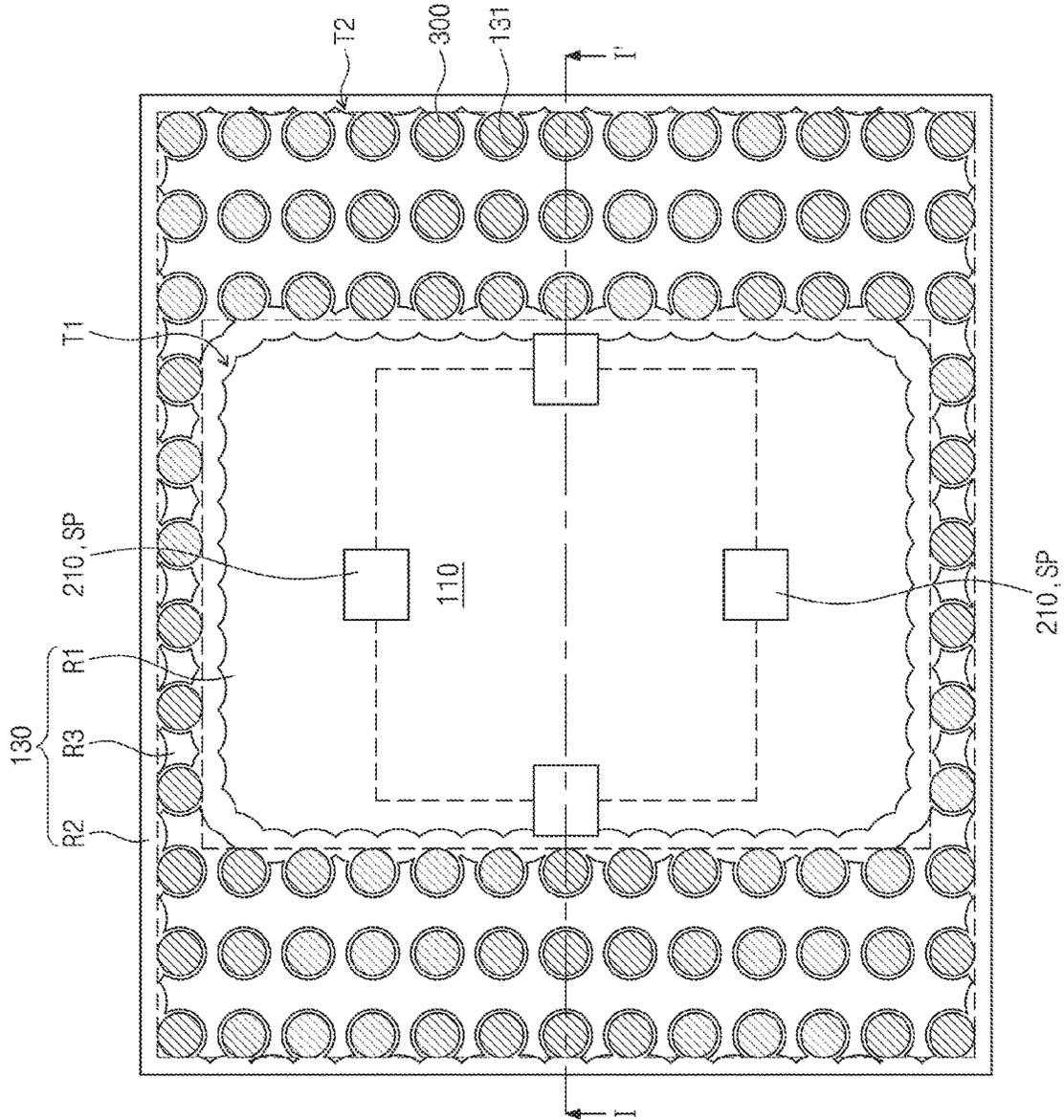


FIG. 4A

FIG. 4B

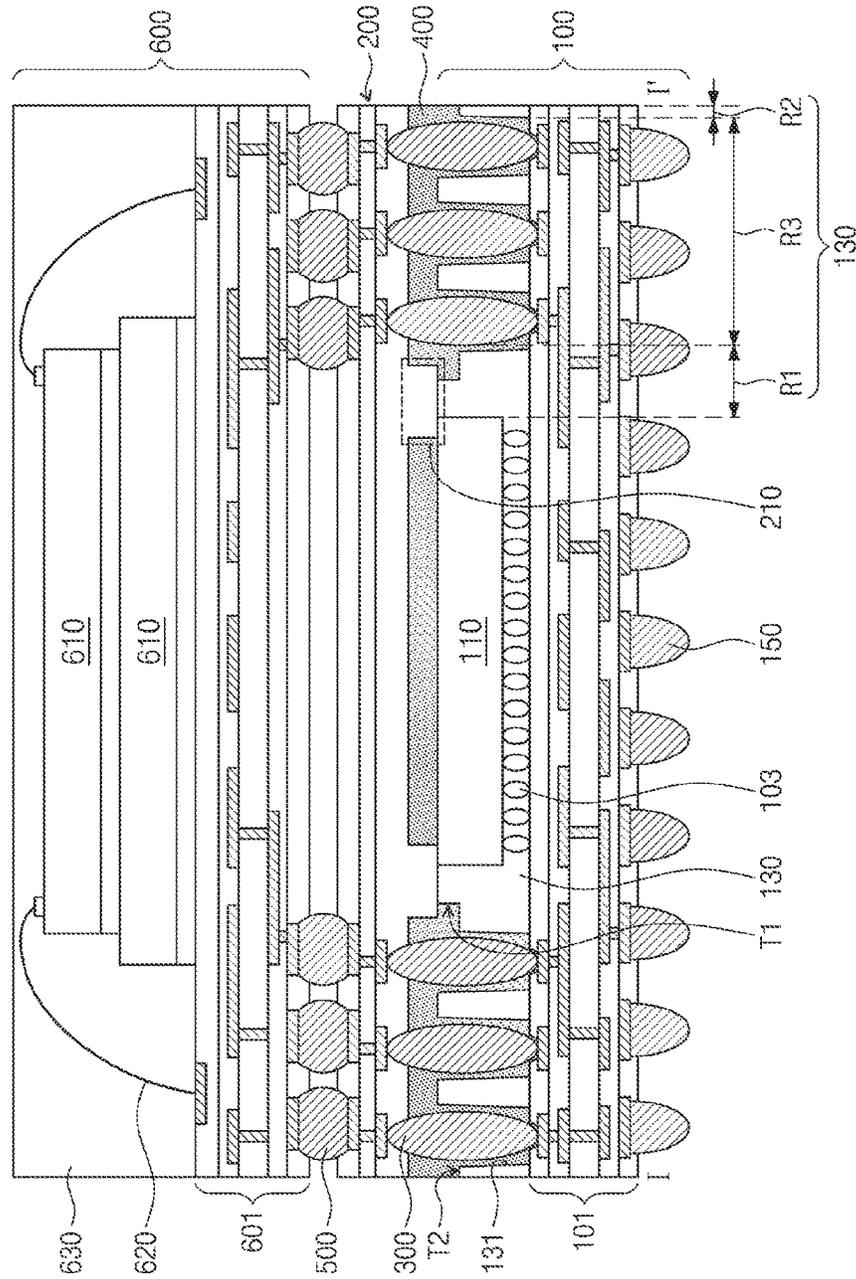
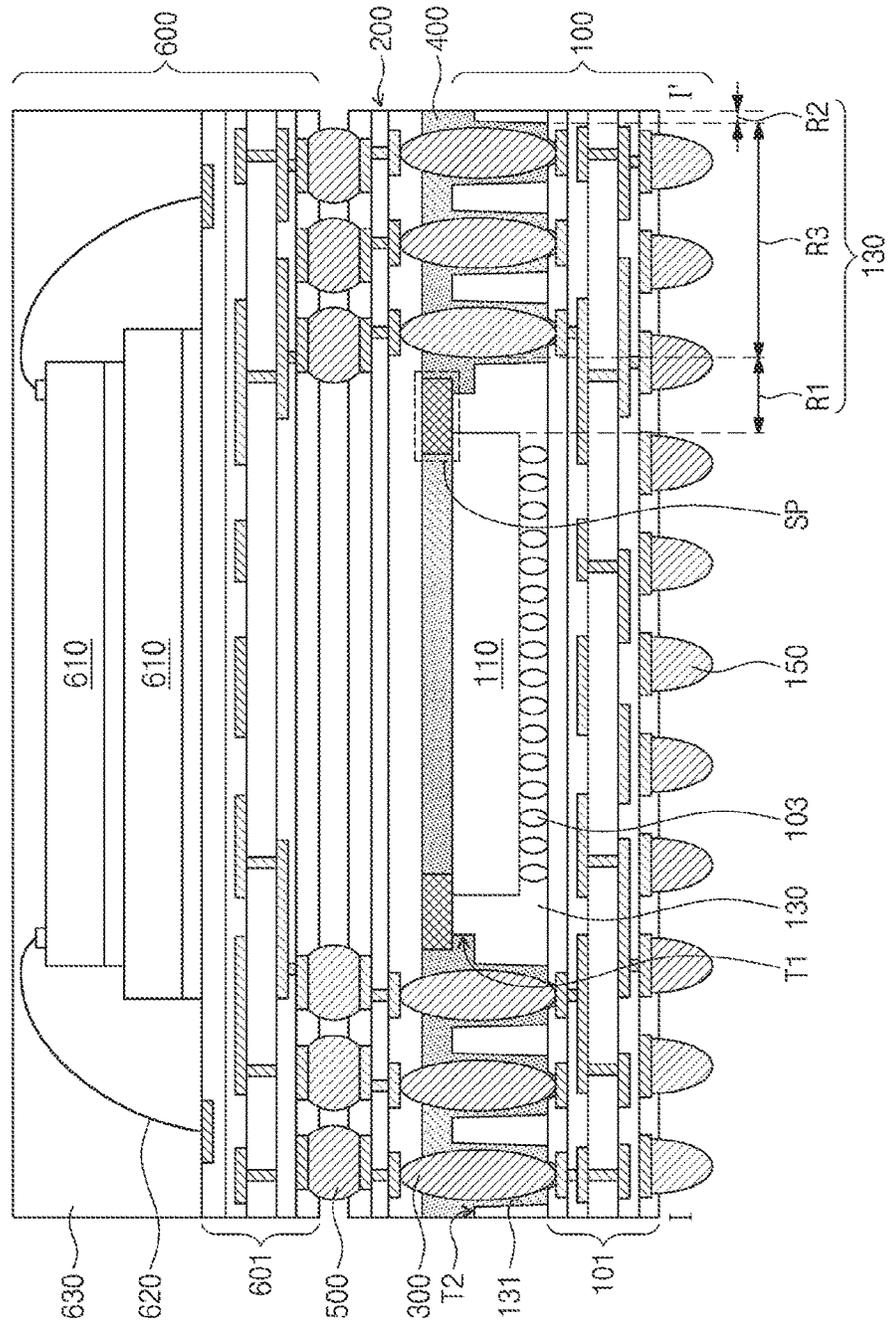


FIG. 4C



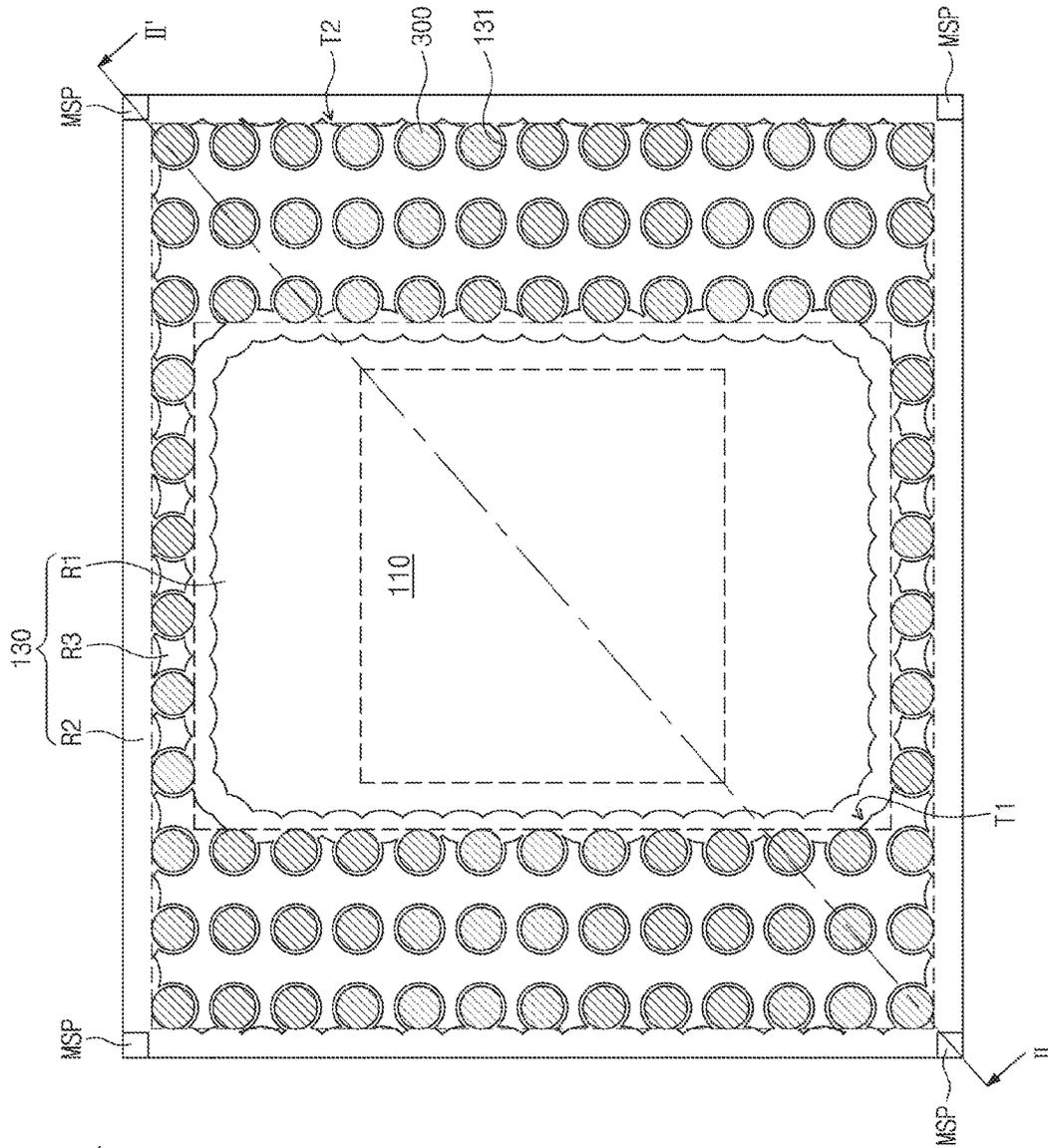


FIG. 5A

FIG. 6

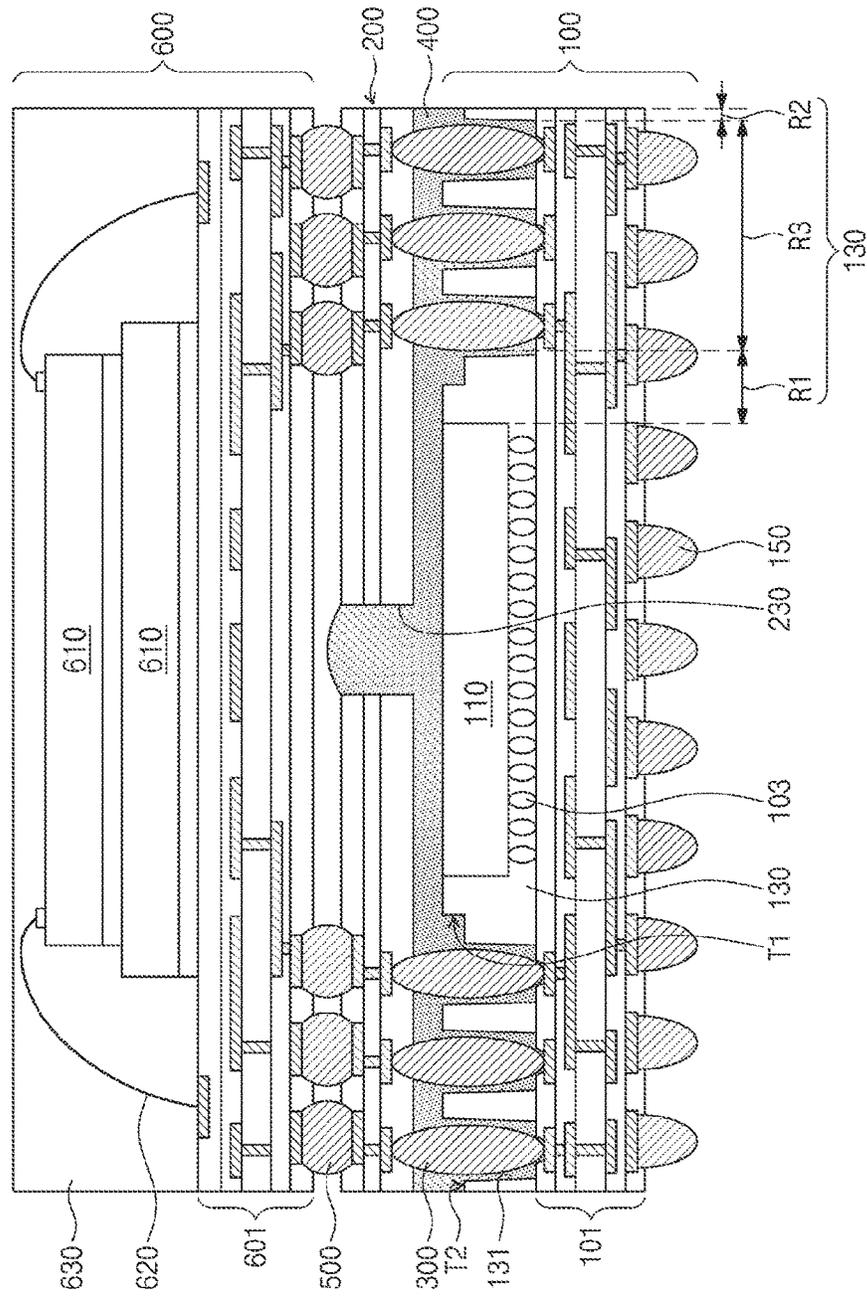


FIG. 7

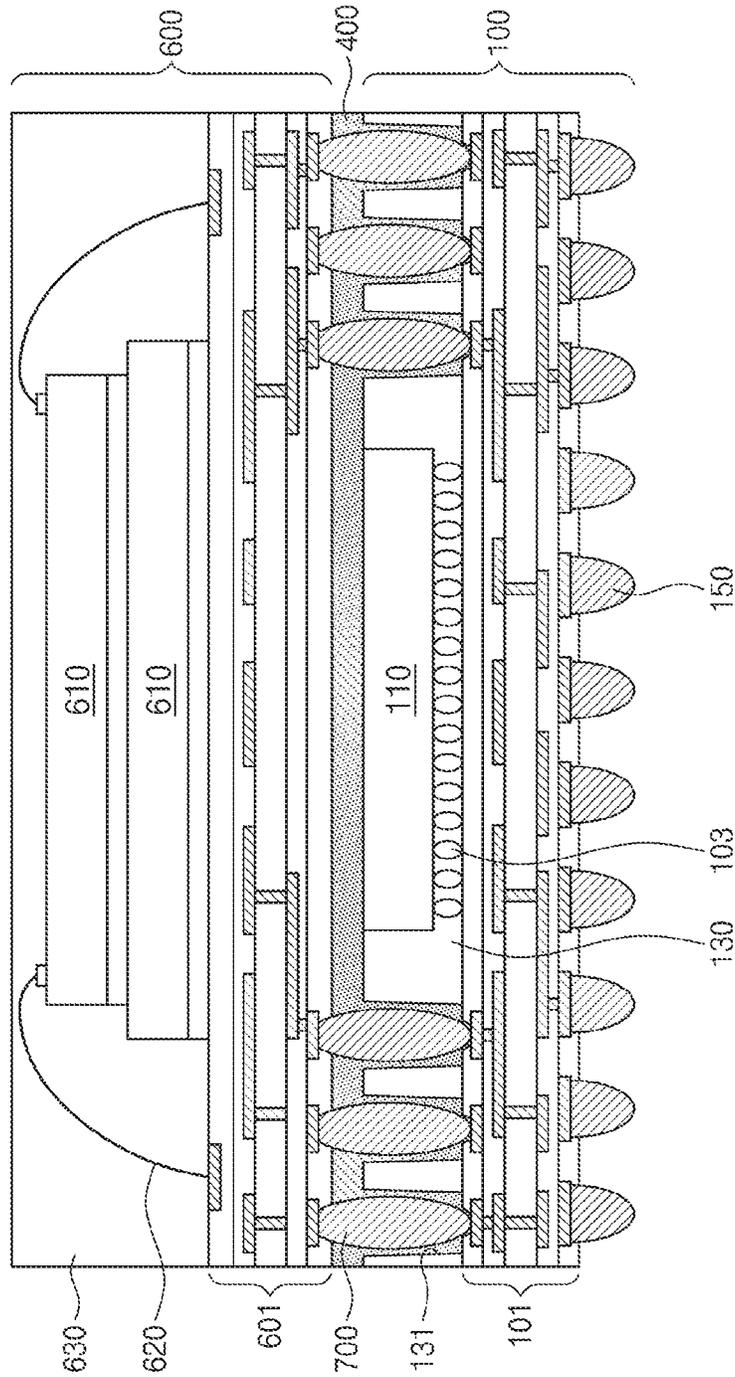


FIG. 8A

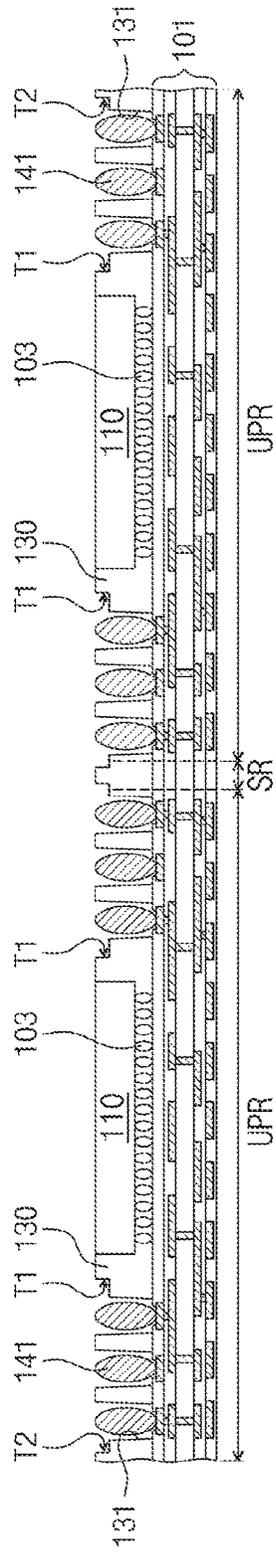


FIG. 8B

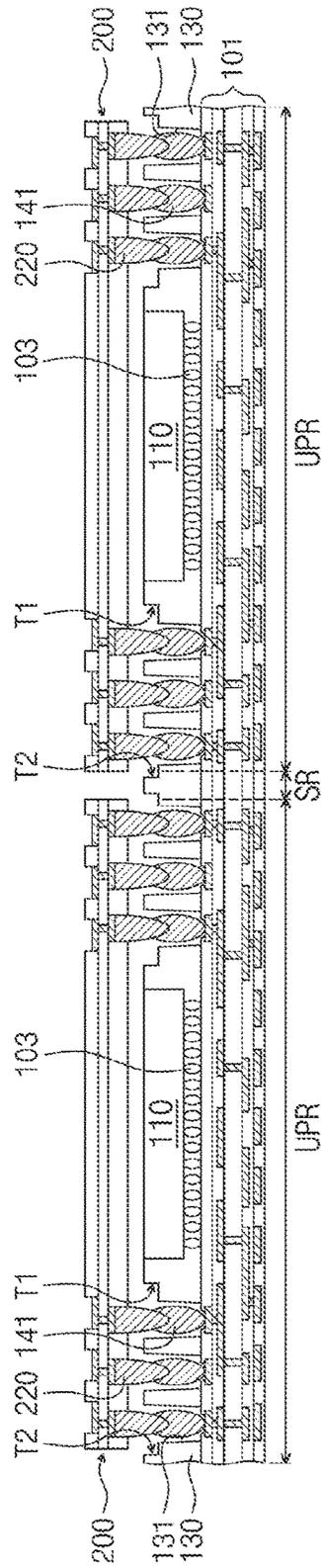


FIG. 9A

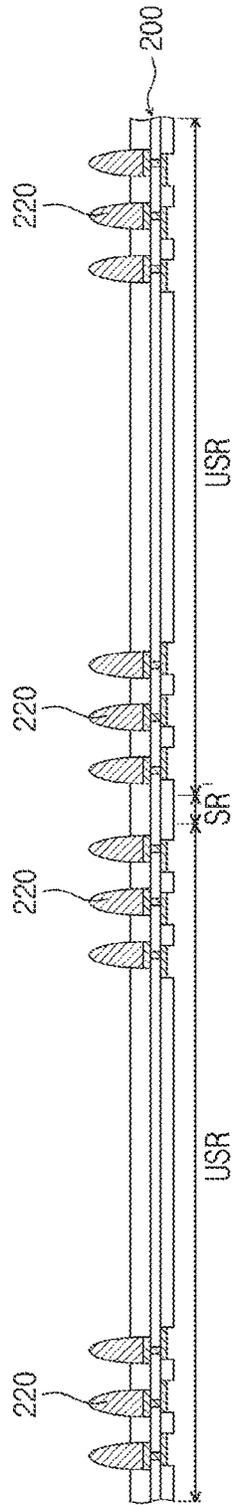


FIG. 9B

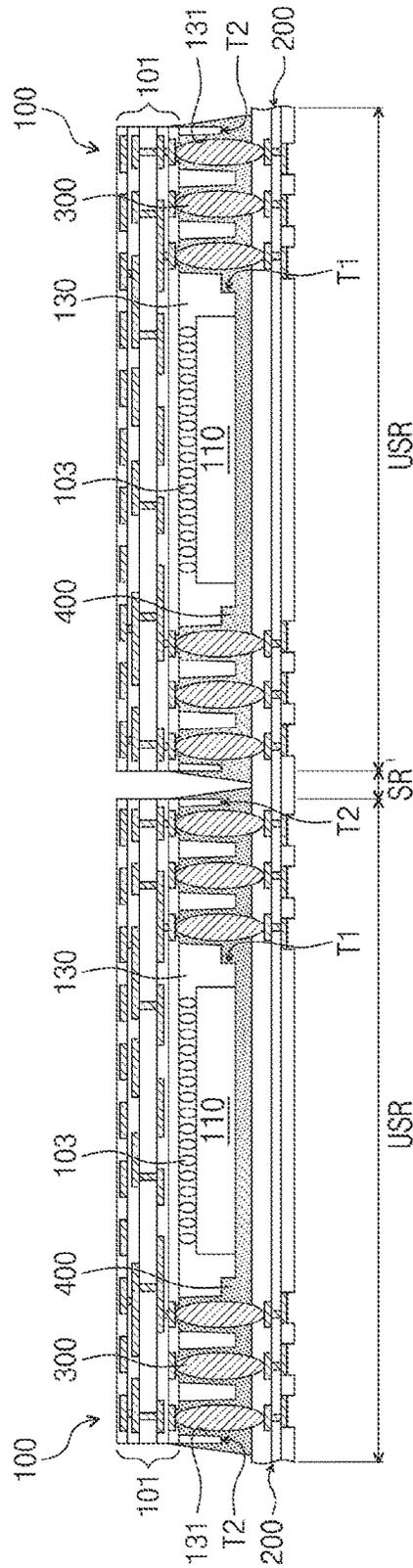


FIG. 9C

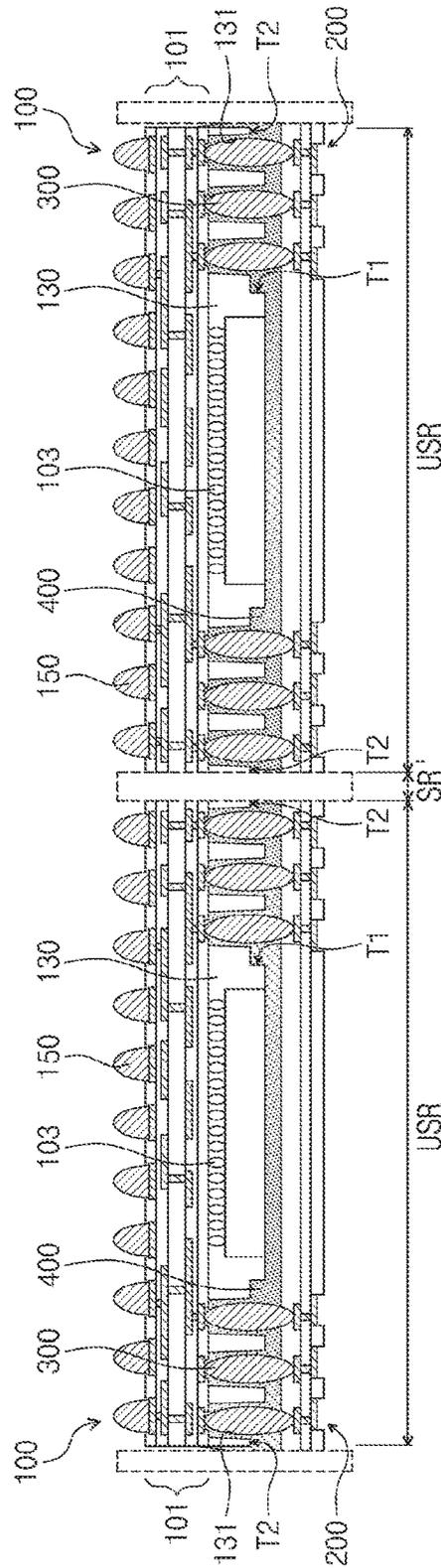


FIG. 10A

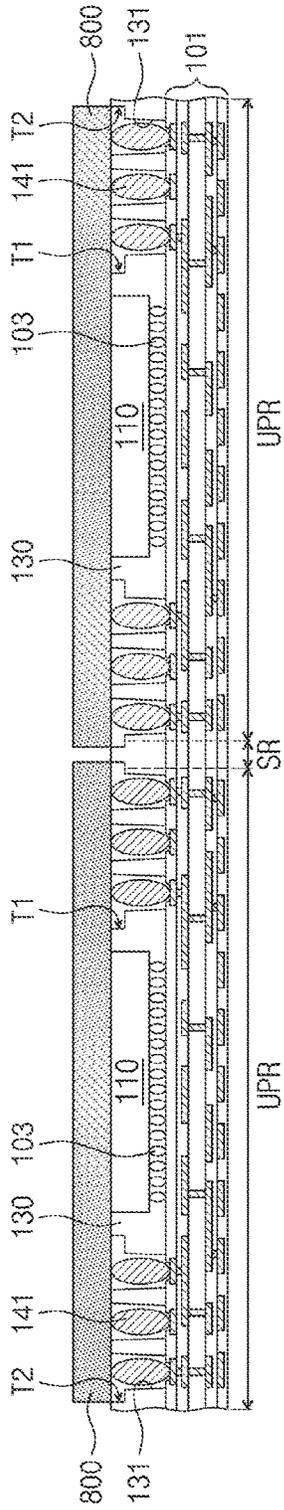


FIG. 10B

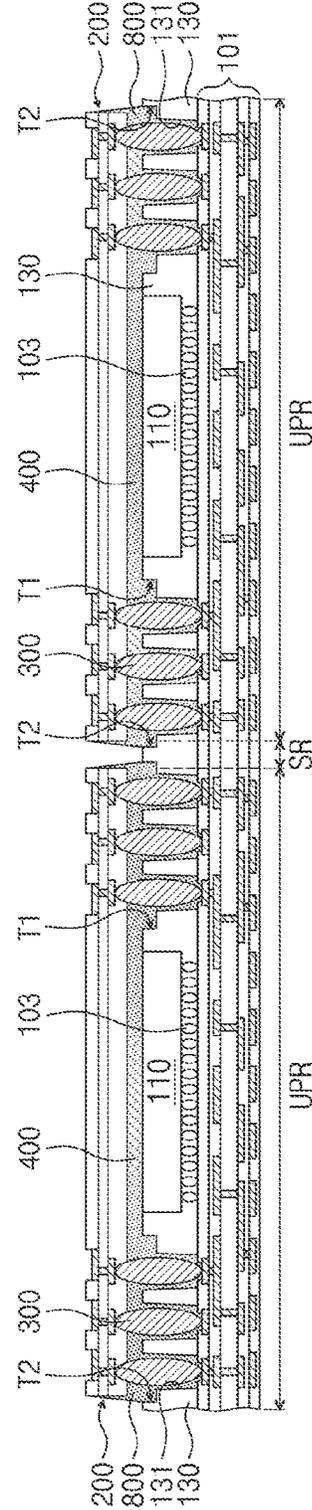


FIG. 11

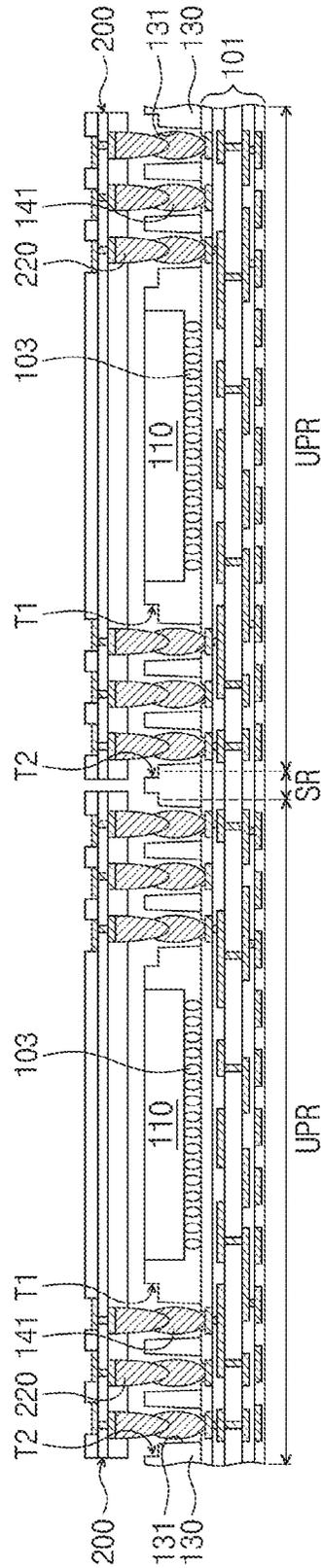
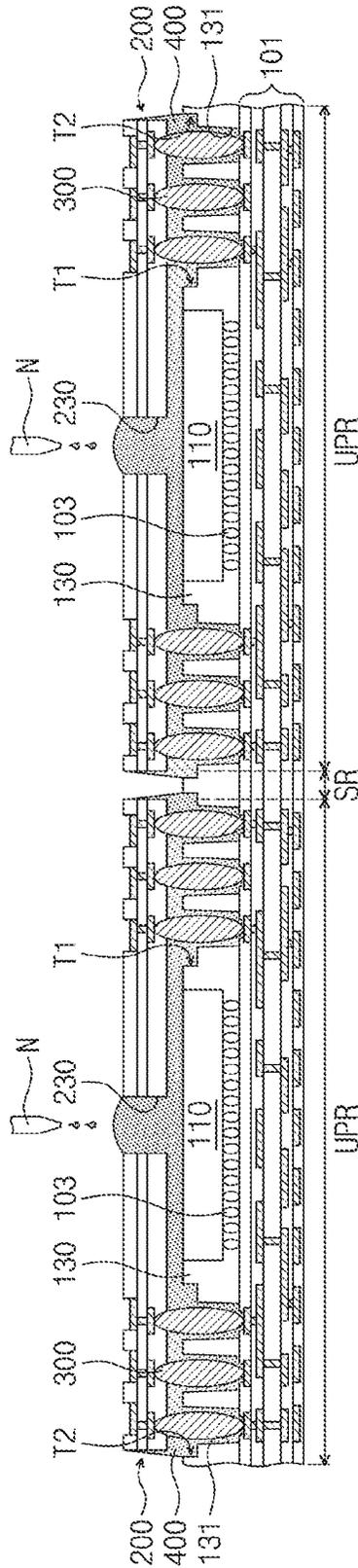


FIG. 12



SEMICONDUCTOR PACKAGE

PRIORITY STATEMENT

This U.S. non-provisional patent application claims priority under 35 U.S.C. § 119 to Korean Patent Application Nos. 10-2016-0155195 and 10-2017-0051203, filed on Nov. 21, 2016 and Apr. 20, 2017, in the Korean Intellectual Property Office, the disclosure of which is hereby incorporated by reference in its entirety.

BACKGROUND

The inventive concepts relate to a semiconductor package and, more particularly, to a semiconductor package having a stack of chips such as a package-on-package (PoP).

As high-capacity, thin and small semiconductor devices and electronic products including the same have become increasingly in demand in the electronics industry, various techniques of packaging chips or die of semiconductor devices been developed. In one of these packaging techniques, various semiconductor chips are stacked to realize a high-density semiconductor device. According to this technique, semiconductor chips having various functions may be integrated on a smaller area, i.e., may have a smaller footprint, than a general package having one semiconductor chip that performs all of such functions.

However, the yield of semiconductor packages manufactured by the packaging technique of stacking a plurality of semiconductor chips tends to be relatively low compared to the yield of semiconductor packages manufactured by the technique of packaging one semiconductor chip. A technique of stacking a package on another package (i.e., a package-on-package (PoP) technique) has been developed to ensure a high product yield of high-density devices.

Since semiconductor packages used in the PoP technique are tested in advance, the failure rate of final products may be reduced. These PoP-type semiconductor packages may be used to achieve miniaturization and provide a multi-function characteristic required for today's electronic portable devices and mobile products.

SUMMARY

According to an aspect of the inventive concepts, a semiconductor package includes a first substrate, a semiconductor chip disposed on the first substrate, a mold layer covering sides of the semiconductor chip and including a through-hole, a second substrate disposed on the semiconductor chip and extending over the mold layer, a connection terminal disposed in the through-hole as interposed between the first substrate and the second substrate, and an underfill resin layer occupying a region between the semiconductor chip and the second substrate and extending contiguously from said region into the through-hole.

According to another aspect of the inventive concepts, a semiconductor package includes a lower package, an upper package disposed on the lower package, an interposer substrate interposed between the lower package and the upper package and including a layer of electrically conductive wiring, an underfill resin layer occupying a region between the lower package and the interposer substrate, and a connection terminal disposed between the lower package and the interposer substrate. The lower package comprises a substrate, a semiconductor chip disposed on the substrate, and a mold layer covering sides of the semiconductor chip and including a through-hole. The connection terminal is

disposed in the through-hole and electrically connects the lower package to the interposer substrate, the connection terminal occupies a portion of the through-hole, and the underfill resin layer fills a region of the through-hole that is not occupied by the connection terminal.

According to yet another aspect of the inventive concepts, a semiconductor package includes

a first package substrate including a layer of electrically conductive wiring, a first semiconductor chip disposed on the first package substrate, the first package substrate including a first insulating layer and a first layer of electrically conductive wiring, a mold layer covering sides of the semiconductor chip and including through-holes, a second substrate disposed on the first semiconductor chip and extending over the mold layer and including a second insulating layer and a second layer of electrically conductive wiring, a second semiconductor chip disposed on and electrically connected to the second substrate, connection terminals disposed in the through-holes, respectively, and electrically connect the first substrate to the second substrate, and a connection terminal-protecting layer occupying a region between the semiconductor chip and the second substrate and extending contiguously from said region into the through-holes. Each of the connection terminals occupies a portion of a respective one of the through-holes in which it is disposed, and the connection terminal-protecting layer fills regions of the through-holes that are not occupied by the connection terminals.

BRIEF DESCRIPTION OF THE DRAWINGS

The inventive concepts will become more apparent in view of the attached drawings and accompanying detailed description.

FIG. 1 is a cross-sectional view illustrating an example of a semiconductor package according to the inventive concepts.

FIG. 2A is a plan view illustrating examples of a semiconductor package according to the inventive concepts.

FIG. 2B is a cross-sectional view of an example of the semiconductor package of FIG. 2A taken along line I-I'.

FIG. 3A is a plan view illustrating examples of a semiconductor package according to the inventive concepts.

FIG. 3B is a cross-sectional view of an example of the semiconductor package of FIG. 3A taken along line I-I'.

FIG. 4A is a plan view illustrating examples of a semiconductor package according to the inventive concepts.

FIGS. 4B and 4C are cross-sectional views of examples of semiconductor packages of FIG. 4A taken along line I-I'.

FIG. 5A is a plan view illustrating examples of a semiconductor package according to the inventive concepts.

FIG. 5B is a cross-sectional view of an example of a semiconductor package of FIG. 5A taken along line II-II'.

FIG. 6 is a cross-sectional view illustrating a semiconductor package according to the inventive concepts.

FIG. 7 is a cross-sectional view illustrating a semiconductor package according to the inventive concepts.

FIGS. 8A, 8B, 8C and 8D are cross-sectional views of semiconductor packages during the course of their manufacture and together illustrate a manufacturing method according to the inventive concepts.

FIGS. 9A, 9B and 9C are cross-sectional views of semiconductor packages during the course of their manufacture and together illustrate a manufacturing method according to the inventive concepts.

FIGS. 10A and 10B are cross-sectional views of semiconductor packages during the course of their manufacture and together illustrate a manufacturing method according to the inventive concepts.

FIG. 11 is a cross-sectional view of semiconductor packages during the course of their manufacture and together illustrate a manufacturing method according to the inventive concepts.

FIG. 12 is a cross-sectional view of semiconductor packages during the course of their manufacture and illustrates a manufacturing method according to the inventive concepts.

DETAILED DESCRIPTION

FIG. 1 is a cross-sectional view illustrating a semiconductor package according to some examples of the inventive concepts.

Referring to FIG. 1, a semiconductor package may include a lower package 100, an interposer substrate 200, lower connection terminals 300, an underfill resin layer 400, upper connection terminals 500, and an upper package 600.

The lower package 100 may include a lower substrate 101, a lower semiconductor chip 110, a lower mold layer 130, and external terminals 150. The lower substrate 101 may be a printed circuit board (PCB). The lower substrate 101 may include an insulating layer and a layer of electrically conductive wiring thereon. The lower substrate 101 may be a multi-layered PCB. For example, the lower substrate 101 may be referred to as a first package substrate and may include a plurality of stacked insulating layers and internal interconnection lines disposed between the insulating layers, and vias connecting layers of the metal interconnection lines to one another. An exemplary one of the insulating layers, e.g., a first insulating layer, is labeled IL in FIG. 1 and an exemplary set of the metal interconnection lines constituting a first layer of electrically conductive wiring is labeled CW in FIG. 1. Other examples of the lower package 100 described later on and designated by the same reference numeral have similar features.

The lower semiconductor chip 110 may be disposed on a top surface of the lower substrate 101. The lower semiconductor chip 110 may be mounted on the top surface of the lower substrate 101 by a flip chip bonding technique.

The lower semiconductor chip 110 may be a logic semiconductor chip or a memory semiconductor chip. Or both a logic semiconductor chip and a memory semiconductor chip may be disposed on a top surface of the lower substrate 101. Otherwise, lower semiconductor chip 110 may be a chip function as a logic semiconductor chip and a memory semiconductor chip. The lower semiconductor chip 110 and the lower substrate 101 may be electrically connected to each other through chip connection parts 103 disposed between the lower semiconductor chip 110 and the top surface of the lower substrate 101. The chip connection parts 103 may include, for example, solder balls.

The lower mold layer 130 may be disposed on sidewalls of the lower semiconductor chip 110. For example, the lower mold layer 130 may be disposed on the lower substrate 101 to cover the sidewalls of the lower semiconductor chip 110. The lower mold layer 130 may include an epoxy mold compound (EMC), an epoxy-based resin, or polyimide. The lower mold layer 130 may further include a silica filler.

A top surface of the lower mold layer 130 may be substantially coplanar with a top surface of the lower semiconductor chip 110. The lower mold layer 130 may fill a space between the lower substrate 101 and the lower semiconductor chip 110. The lower mold layer 130 may

have through-holes 131. The through-holes 131 may be arranged to surround the lower semiconductor chip 110 when viewed in a plan view. Portions of the top surface of the lower substrate 101 may be exposed by the through-holes 131. For example, surfaces defining bottom of the through-holes 131 may correspond to the portions of the top surface of the lower substrate 101.

The external terminals 150 may be disposed on a bottom surface of the lower substrate 101. The external terminals 150 may be electrically connected to the lower semiconductor chip 110 through the internal interconnection lines of the lower substrate 101. The external terminals 150 may include, for example, solder balls.

The interposer substrate 200 may be disposed on a lower package 100. The interposer substrate 200 may electrically connect the lower package 100 to the upper package 600. The interposer substrate 200 may include an insulating layer and a layer of electrically conductive wiring thereon. The interposer substrate 200 may be multi-layered. For example, the interposer substrate 200 may include insulating layers and metal interconnection lines, which are alternately stacked, and vias connecting layers of the metal interconnection lines to one another.

The lower connection terminals 300 may be disposed between the interposer substrate 200 and the lower substrate 101. The lower connection terminals 300 may electrically connect the lower package 100 to the interposer substrate 200. The lower connection terminals 300 may be provided in the through-holes 131. In some examples, the lower connection terminals 300 protrude upward from the through-holes 131. In other words, the lower connection terminals 300 may have protruding portions above the level of the top surface of the lower mold layer 130. In some examples, sidewalls of the lower connection terminals 300 disposed in the through-holes 131 may be spaced apart from inner wall surfaces defining the sides of the through-holes 131. The lower connection terminals 300 may include at least one of tin (Sn), lead (Pb), nickel (Ni), gold (Au), silver (Ag), copper (Cu), and bismuth (Bi).

The underfill resin layer 400 may be disposed between the lower package 100 and the interposer substrate 200. The underfill resin layer 400 may fill a space between the lower semiconductor chip 110 and the interposer substrate 200, a space between the lower mold layer 130 and the interposer substrate 200, and regions of the through-holes 131 not occupied by the lower connection terminals 300. For example, the underfill resin layer 400 may extend contiguously from the region between the lower semiconductor chip 110 and the interposer substrate 200 into the region between the lower mold layer 130 and the interposer substrate 200 within the through-holes 131. The underfill resin layer 400 may surround the lower connection terminals 300. For example, the underfill resin layer 400 may cover outer circumferential surfaces (referred to hereinafter as “sidewalls”) of the lower connection terminals 300. In more detail, each of the lower connection terminals 300 may include the protruding portion situated above the level of the top surface of the lower mold layer 130, and a lower portion situated beneath the level of the top surface of the lower mold layer 130 (i.e., disposed in the through-hole 131). The underfill resin layer 400 may cover sidewalls of the protruding portions of the lower connection terminals 300 and sidewalls of the lower portions of the lower connection terminals 300. The underfill resin layer 400 may be in contact with the top surface of the lower semiconductor chip 110, the top surface of the lower mold layer 130, and the inner wall surfaces defining the sides of the through-holes

131. The underfill resin layer 400 may be formed of an epoxy-based resin, benzocyclobutene or polyimide. The underfill resin layer 400 may further include a silica filler. In certain examples, the underfill resin layer 400 includes an adhesive and a flux. The flux may include an oxide-removing agent. In certain examples, the underfill resin layer 400 includes a silica filler or a flux. In certain examples, the underfill resin layer 400 includes non-conductive paste.

According to the examples of the inventive concepts, the underfill resin layer 400 disposed between the lower package 100 and the interposer substrate 200 surrounds outer circumferential surfaces of the lower connection terminals 300 to support the lower connection terminals 300. Stress occurring between the lower package 100 and the interposer substrate 200 may be applied to the lower connection terminals 300. However, the underfill resin layer 400 reduces the stress otherwise applied to the lower connection terminals 300, and thus may serve as a connection terminal-protecting layer to prevent or inhibit a crack from occurring in the lower connection terminals 300.

The upper package 600 may be disposed on the interposer substrate 200. The upper package 600 may include an upper substrate 601, upper semiconductor chips 610, bonding wires 620, and an upper mold layer 630. The upper substrate 601 may be a printed circuit board (PCB). The upper substrate 601 may include an insulating layer and a layer of electrically conductive wiring thereon. The upper substrate 601 may be a multi-layered PCB. For example, the upper substrate 601 may include a plurality of stacked insulating layers and internal interconnection lines disposed between the insulating layers, and vias electrically connecting layers of the interconnection lines to one another.

The upper semiconductor chips 610 may be sequentially stacked one on another on a top surface of the upper substrate 601. The upper semiconductor chips 610 may be fixed on the top surface of the upper substrate 601 by adhesive layers. For example, each of the upper semiconductor chips 610 may be a logic semiconductor chip or a memory semiconductor chip. The upper semiconductor chips 610 may be the same kind of semiconductor chips or different kinds of semiconductor chips. In the present example, the upper package 600 includes two upper semiconductor chips 610. However, the inventive concepts are not limited to the upper package 600 having any particular number of upper semiconductor chips 610.

The bonding wires 620 may electrically connect the upper semiconductor chips 610 to the upper substrate 601. In the present example, the upper semiconductor chips 610 are mounted on the upper substrate 601 by a wire bonding technique using the bonding wires 620. However, examples of the inventive concepts are not limited thereto. In certain examples, the upper semiconductor chips 610 are mounted on the upper substrate 601 by a flip chip bonding technique. The upper mold layer 630 may be disposed on the upper substrate 601. The upper mold layer 630 may cover the upper semiconductor chips 610 and the bonding wires 620.

FIG. 2A is a plan view illustrating a semiconductor package according to some examples of the inventive concepts. FIG. 2B is a cross-sectional view taken along a line I-I' of FIG. 2A. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators. In addition, the descriptions of the same elements as in the above examples will be omitted or mentioned briefly for the sake of brevity.

Referring to FIGS. 2A and 2B, the lower mold layer 130 may include a first region R1, a second region R2, and a third

region R3. The first region R1 of the lower mold layer 130 may be disposed between the lower semiconductor chip 110 and the lower connection terminals 300. For example, the first region R1 of the lower mold layer 130 may be disposed between the lower semiconductor chip 110 and the lower connection terminals 300 closest to the lower semiconductor chip 110. In other words, the lower connection terminals 300 may not be disposed in the first region R1 of the lower mold layer 130. The second region R2 of the lower mold layer 130 may be disposed at a side of the first region R1 of the lower mold layer 130. The second region R2 of the lower mold layer 130 may correspond to an edge region of the lower mold layer 130, i.e. may include the outer peripheral portion of the lower mold layer 130. The lower connection terminals 300 may not be disposed in the second region R2 of the lower mold layer 130. The third region R3 of the lower mold layer 130 may be disposed between the first region R1 and the second region R2. The lower connection terminals 300 may be disposed in the third region R3 of the lower mold layer 130.

The lower mold layer 130 may include a first extension trench T1. The first extension trench T1 may be formed in the first region R1 of the lower mold layer 130. For example, the first extension trench T1 may be disposed between the lower semiconductor chip 110 and the lower connection terminals 300 closest to the lower semiconductor chip 110. The first extension trench T1 may have a line or ring shape and extend between the lower semiconductor chip 110 and the lower connection terminals 300 closest to the lower semiconductor chip 110. The first extension trench T1 may be open to, and more specifically, may open into upper portions of the through-holes 131 in which the lower connection terminals 300 closest to the lower semiconductor chip 110 are provided. Thus, sum of the width of an upper portion of each through-hole 131 (diameter of the through-hole in the case of a circular through-hole) and the width of the first extension trench T1 open thereto may be greater than the width of the lower portion of the through-hole 131.

The lower mold layer 130 thus may be recessed, by virtue of the first extension trench T1, from the top surface of the lower semiconductor chip 110. That is, a surface lower of the mold layer 130 defining the bottom of the first extension trench T1 may be disposed at a level that is lower than the top surface of the lower semiconductor chip 110 and is higher than the bottoms of the through-holes 131. The bottom of the first extension trench T1 may be lower than a top surface of a portion of first region R1 of the lower mold layer 130 disposed between the first extension trench T1 and the lower semiconductor chip 110 and may be lower than a top surface of the third region R3 of the lower mold layer 130.

The lower mold layer 130 may include a second extension trench T2. The second extension trench T2 may be formed in the second region R2 of the lower mold layer 130. For example, the second extension trench T2 may be disposed between outer sidewalls of the lower mold layer 130 and the lower connection terminals 300 closest to the outer sidewalls of the lower mold layer 130. The second extension trench T2 may have a line or ring shape and extend between the outer sidewalls of the lower mold layer 130 and the lower connection terminals 300 closest to the outer sidewalls of the lower mold layer 130. The second extension trench T2 may open to upper portions of the through-holes 131 in which the lower connection terminals 300 closest to the outer sidewalls of the lower mold layer 130 are provided. Thus, the sum of widths of an upper portion of each through-hole 131 and the

second extension trench T2 open thereto may be greater than width of the lower portion of the through-hole 131.

The lower mold layer 130 may be recessed from the top surface of the lower semiconductor chip 110 by virtue of the second extension trench T2. That is, a surface of the lower mold layer 130 defining the bottom the second extension trench T2 may be disposed at a level that is lower than the top surface of the lower semiconductor chip 110 and is higher than bottoms of the through-holes 131. The bottom of the second extension trench T2 may be disposed at a lower level than the top surface of the third region R3 of the lower mold layer 130. In some examples, therefore, heights of the outer sidewalls of the lower mold layer 130 may be less than the distance from the top surface of the lower substrate 101 to the top surface of the lower semiconductor chip 110.

The underfill resin layer 400 may fill the first extension trench T1 and the second extension trench T2. The underfill resin layer 400 may be in contact with the surfaces defining (the bottom and side of) the first extension trench T1 and (the bottom of) the second extension trench T2.

FIG. 3A is a plan view illustrating a semiconductor package according to some examples of the inventive concepts. FIG. 3B is a cross-sectional view taken along a line I-I' of FIG. 3A. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators. In addition, the descriptions to the same elements as in the above examples will be omitted or mentioned briefly for the sake of brevity.

Referring to FIGS. 3A and 3B, lower connection terminals 300 may include first lower connection terminals 300a and second lower connection terminals 300b. The first lower connection terminals 300a may be arranged to surround the lower semiconductor chip 110 when viewed in a plan view. The second lower connection terminals 300b may be disposed at a side of the first lower connection terminals 300a.

The first extension trench T1 may be disposed in the first region R1 of the lower mold layer 130. For example, the first extension trench T1 may be disposed between the lower semiconductor chip 110 and the first lower connection terminals 300a. The second extension trench T2 may be disposed in the second region R2 of the lower mold layer 130. For example, the second extension trench T2 may extend from between one outer sidewall of the lower mold layer 130 and the second lower connection terminals 300b closest to the one outer sidewall of the lower mold layer 130 into between another outer sidewall of the lower mold layer 130 and the first lower connection terminals 300a closest to the another outer sidewall of the lower mold layer 130. The another outer sidewall of the lower mold layer 130 may extend in a direction intersecting (e.g. perpendicular to) the one outer sidewall of the lower mold layer 130.

The lower mold layer 130 may include third extension trenches T3. The third extension trenches T3 may be disposed in the third region R3 of the lower mold layer 130. For example, one of the third extension trenches T3 may be disposed between the first lower connection terminals 300a and the second lower connection terminals 300a adjacent to the first lower connection terminals 300a and may extend (longitudinally) in one direction (e.g., top to bottom in FIG. 3A). Another of the third extension trenches T3 may be disposed between the second lower connection terminals 300b adjacent to each other and may extend in the one direction (e.g., top to bottom in FIG. 3A). The one of the third extension trenches T3 may open to the through-holes 131 provided with the first lower connection terminals 300a adjacent thereto and the through-holes 131 provided with the

second lower connection terminals 300b adjacent thereto. The another of the third extension trenches T3 may be open to the through-holes 131 provided with the second lower connection terminals 300b adjacent thereto. The sum of the widths of the upper portion of each of the through-holes 131 and the third extension trench(es) T3 open thereto may be greater than the width of the lower portion of the through-holes 131.

In some examples, the first and third extension trenches T1 and T3 may meet each other so as to be open to each other. In other words, the first and third extension trenches T1 and T3 meeting each other may be considered to constitute one trench. The second extension trench T2 may be spaced apart from the first and third extension trenches T1 and T3 but may be connected to the first and third extension trenches T1 and T3 through the through-holes 131. In certain other examples, even though not shown in the drawings, the first to third extension trenches T1, T2, and T3 may be spaced apart from each other but may be connected to each other through the through-holes 131.

The underfill resin layer 400 may fill the first extension trench T1, the second extension trench T2, and the third extension trenches T3. The underfill resin layer 400 may be in contact with surfaces defining (the bottom and side of) the first extension trench T1, (the bottom of) the second extension trench T2, and (the bottom of) the third extension trenches T3.

FIG. 4A is a plan view illustrating a semiconductor package according to some examples of the inventive concepts. FIG. 4B is a cross-sectional view taken along a line I-I' of FIG. 4A. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators, and the descriptions thereto will be omitted for the sake of brevity.

Referring to FIGS. 4A and 4B, the interposer substrate 200 may include protrusions 210 protruding from a bottom surface of the interposer substrate 200. The protrusions 210 may extend from the bottom surface of the interposer substrate 200 into the underfill resin layer 400 so as to be in contact with the top surface of the lower semiconductor chip 110. For example, the protrusions 210 may extend from the bottom surface of the interposer substrate 200 into the underfill resin layer 400 and may have a surface coplanar with an interface (or a boundary) between the lower semiconductor chip 110 and the lower mold layer 130. The protrusions 210 may be in contact with portions of the top surface of the lower semiconductor chip 110 and portions of the top surface of the first region R1 of the lower mold layer 130. The protrusions 210 may be spaced apart from each other. The protrusions 210 may establish or maintain a distance between the lower package 100 and the interposer substrate 200. The protrusions 210 may be unitary parts of a layer of the interposer substrate 200, i.e., a lowermost layer of the interposer substrate 200. For example, the protrusions 210 may include the same material as the lowermost one of the stacked layers of the interposer substrate 200. Thus, the protrusions 210 may include an insulating material, e.g., a photo solder resist (PSR).

FIG. 4C is a cross-sectional view taken along the line I-I' of FIG. 4A to illustrate a semiconductor package according to some examples of the inventive concepts. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators, and the descriptions thereto will be omitted for the sake of brevity.

Referring to FIG. 4C, support patterns SP may be disposed between the lower package 100 and the interposer

substrate **200**. The support patterns SP may be spaced apart from each other. The support patterns SP may have bottom surfaces coplanar with the interface (or the boundary) between the lower mold layer **130** and the lower semiconductor chip **110**. The support patterns SP may be in contact with portions of the top surface of the lower semiconductor chip **110**, portions of the top surface of the first region R1 of the lower mold layer **130**, and portions of the bottom surface of the interposer substrate **200**. The support patterns SP may establish or maintain a distance between the lower package **100** and the interposer substrate **200**. The support patterns SP may include an epoxy-based resin or a metal material (e.g., copper).

FIG. 5A is a plan view illustrating a semiconductor package according to some examples of the inventive concepts. FIG. 5B is a cross-sectional view taken along line II-II' of FIG. 5A. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators, and the descriptions thereto will be omitted for the sake of brevity.

Referring to FIGS. 5A and 5B, the lower mold layer **130** may include mold support patterns MSP protruding from a top surface of the lower mold layer **130**. The mold support patterns MSP may be unitary with the other portions of the lower mold layer **130**. The mold support patterns MSP may be disposed in the second extension trench T2. The mold support patterns MSP may be disposed at corners of the lower mold layer **130**. In some examples, vertexes of the interposer substrate **200**, at which the bottom surface and outer sidewalls of the interposer substrate **200** meet each other, may overlap top surfaces of the mold support patterns MSP as viewed in a plan view. In a case in which the interposer substrate **200** is bent such that its top surface has a convex shape, the vertexes of the interposer substrate **200** may meet the top surfaces of the mold support patterns MSP to establish or secure distances between end portions of the lower package **100** and end portions of the interposer substrate **200**.

FIG. 6 is a cross-sectional view illustrating a semiconductor package according to some examples of the inventive concepts. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators, and the descriptions thereto will be omitted for the sake of brevity.

Referring to FIG. 6, the interposer substrate **200** may include a through portion **230** (opening extending through the layers of the interposer substrate). The through portion **230** may be an empty region. The through portion **230** may be disposed in a central portion of the interposer substrate **200**. A portion of the underfill resin layer **400** may be exposed through the through portion **230**. The underfill resin layer **400** may fill the through portion **230**. In some examples, the underfill resin layer **400** filling the through portion **230** protrudes upwardly from the top surface of the interposer substrate **200**, and thus a top surface of the underfill resin layer **400** filling the through portion **230** may be disposed at a higher level than the top surface of the interposer substrate **200**.

FIG. 7 is a cross-sectional view illustrating a semiconductor package according to some examples of the inventive concepts. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators, and the descriptions thereto will be omitted for the sake of brevity.

Referring to FIG. 7, a semiconductor package may include the lower package **100**, the underfill resin layer **400**, connection terminals **700**, and the upper package **600**.

The connection terminals **700** may be disposed between the lower package **100** and the upper package **600** and may function as a connection path electrically connecting the lower package **100** to the upper package **600**. The connection terminals **700** may be provided in the through-holes **131** of the lower mold layer **130**. The underfill resin layer **400** may fill a space between the lower semiconductor chip **110** and the upper substrate **601**, a space between the upper substrate **601** and the lower mold layer **130**, and portions of the through-holes **131** not occupied by the connection terminals **700**. The underfill resin layer **400** may surround sidewalls of the connection terminals **700**.

In addition, the mold layer **130** and the underfill resin layer **400** of the semiconductor package shown in FIG. 7 may incorporate any of the features associated with the mold layer **130** and the underfill resin layer **400** described above with reference to the examples of FIGS. 2A, 2B-FIG. 6, e.g., extension trenches in the mold layer **130** and/or spacers or mold support patterns MSP.

FIGS. 8A to 8D illustrate a method of manufacture according to the inventive concepts.

Referring to FIG. 8A, lower semiconductor chips **110** may be mounted on a top surface of a lower substrate **101**. The lower substrate **101** may be a printed circuit board (PCB). For example, the lower substrate **101** may include a plurality of stacked insulating layers and internal interconnection lines (layer of wiring) disposed between the insulating layers. The lower substrate **101** may include unit package regions UPR and a scribing region SR. The scribing region SR may be disposed between the unit package regions UPR. Also, each of the unit package regions UPR may be surrounded by the scribing region SR when viewed in a plan view. One lower semiconductor chip **110** may be mounted on each of the unit package regions UPR. Each of the lower semiconductor chips **110** may be a logic semiconductor chip or a memory semiconductor chip. The lower semiconductor chips **110** may be mounted on top surfaces of the unit package regions UPR of the lower substrate **101** by a flip chip-bonding technique. The lower semiconductor chips **110** may be adhered to the top surface of the lower substrate **101** by chip connection parts **103**. In other words, the chip connection parts **103** may be formed between the lower substrate **101** and the lower semiconductor chips **110**. The chip connection parts **103** may include, for example, solder balls.

First terminals **141** may be formed on the top surface of each unit package region UPR around the lower semiconductor chip **110**. The first terminals **141** may be formed using a screen printing technique, an ink-jet technique, or a soldering technique. The first terminals **141** may include solder balls. For example, the first terminals **141** may include at least one of tin (Sn), lead (Pb), nickel (Ni), gold (Au), silver (Ag), copper (Cu), and bismuth (Bi).

A lower mold layer **130** may be formed on the top surfaces of the unit package regions UPR and the scribing region SR of the lower substrate **101**. The lower mold layer **130** may fill spaces between the lower substrate **101** and the lower semiconductor chips **110** and may cover the first terminals **141** and the lower semiconductor chips **110**. The lower mold layer **130** may be formed by a molded underfill (MUF) method. A grinding process may be additionally performed on a top surface of the lower mold layer **130** to planarize the top surface of the lower mold layer **130**. In this case, top surfaces of the lower semiconductor chips **110** may

be exposed. The lower mold layer **130** may include an epoxy mold compound (EMC), an epoxy-based resin, or polyimide.

A first laser drilling process may be performed on the lower mold layer **130** to expose the first terminals **141** buried in the lower mold layer **130**. Thus, through-holes **131** may be formed in the lower mold layer **130**. The first terminals **141** may be provided in the through-holes **131**.

After the through-holes **131** have been formed, a second laser drilling process may be performed on the lower mold layer **130** to form first and second extension trenches **T1** and **T2** in the lower mold layer **130**. Each of the first extension trenches **T1** may be formed between respective one of the lower semiconductor chips **110** and the first terminals **141** closest to the lower semiconductor chip **110**. The first extension trench **T1** may surround the lower semiconductor chip **110** as viewed in a plan view. The first extension trench **T1** may open to the through-holes **131** exposing the first terminals **141** closest to the lower semiconductor chip **110**. For example, upper portions of the through-holes **131** may in effect be expanded by the first extension trench **T1**. The total width of the upper portion of a through-hole **131** and the first extension trench **T1** may be greater than the width of the lower portion of the through-hole **131**. The first extension trench **T1** may be shallower than the through-holes **131**. In other words, a bottom of the first extension trench **T1** may be disposed at a higher level than bottoms of the through-holes **131**. In some examples, the first extension trenches **T1** may be spaced apart from the lower semiconductor chips **110** by a predetermined distance to prevent the lower semiconductor chips **110** from being damaged by the laser used to form the first extension trenches **T1**. Thus, sidewalls of the lower semiconductor chips **110** may not be exposed by the first extension trenches **T1**.

Each of the second extension trenches **T2** may be formed between the scribing region **SR** of the lower substrate **101** and the first terminals **141** closest to the scribing region **SR**. For example, each of the second extension trenches **T2** may be formed in an edge region of the lower mold layer **130** on each of the unit package regions **UPR**. The second extension trench **T2** may be open to the through-holes **131** exposing the first terminals **141** closest to the scribing region **SR**. As a result, upper portions of the through-holes **131** may in effect be expanded by the second extension trench **T2**. Widths of the upper portion of the through-hole **131** and the second extension trench **T2** in total may be greater than the width of the lower portion of the through-hole **131**. The second extension trench **T2** may be shallower than the through-holes **131**. In other words, the bottom of the second extension trench **T2** may be disposed at a higher level than the bottoms of the through-holes **131**.

Referring to FIG. **8B**, interposer substrates **200** may be stacked on the unit package regions **UPR** of the lower substrate **101**. The interposer substrates **200** may be separated from each other and may be stacked on the unit package regions **UPR**, respectively. The interposer substrates **200** may include insulating layers, metal interconnection lines, and second terminals **220**. For example, each of the interposer substrates **200** may have a structure in which the insulating layers and the metal interconnection lines are alternately stacked, and the second terminals **220** are disposed at the bottom of the interposer substrate **200** (i.e., on a bottom surface of an insulating layer) and electrically connected to the metal interconnection lines of the interposer substrate **200**. The second terminals **220** may include at least one of tin (Sn), lead (Pb), nickel (Ni), gold (Au), silver (Ag), copper (Cu), and bismuth (Bi).

The stacking of the interposer substrates **200** on the unit package regions **UPR** of the lower substrate **101** may include providing a flux agent onto surfaces of the second terminals **220** and aligning the second terminals **220** of the interposer substrates **200** with the first terminals **141**, respectively. The second terminals **220** may come into contact with the first terminals **141**. The flux agent may remove oxide layers formed on the surfaces of the first and second terminals **141** and **220** serves to easily unify the first and second terminals **141** and **220** in a subsequent reflow process.

Referring to FIG. **8C**, the reflow process may be performed on the first and second terminals **141** and **220** to form lower connection terminals **300**. The first terminals **141** and the second terminals **220** may be melted in the reflow process, and thus each of the first terminals **141** and each of the second terminals **220**, which are connected to each other, may be unified to form one connection terminal.

An underfill resin layer **400** may be formed in a space between the lower substrate **101** and each of the interposer substrates **200**. The forming of the underfill resin layer **400** may include locating a nozzle **N** at a side of the interposer substrate **200**, filling the space between the interposer substrate **200** and the lower substrate **101** with an underfill resin solution dispensed from the nozzle **N**, and hardening (curing) the underfill resin solution. The underfill resin layer **400** may be formed in a space between the lower semiconductor chip **110** and the interposer substrate **200**, the first extension trenches **T1**, a space between the lower mold layer **130** and the interposer substrate **200**, the through-holes **131**, and the second extension trenches **T2**. The underfill resin layer **400** may be formed to surround sidewalls of the lower connection terminals **300**. The underfill resin layer **400** may include an epoxy-based resin, benzocyclobutene, or polyimide. The underfill resin layer **400** may further include a silica filler. In certain examples, the underfill resin layer **400** includes an adhesive and a flux. The flux may include an oxide-removing agent. In certain examples, the underfill resin layer **400** may include a silica filler or a flux. In certain examples, the underfill resin layer **400** may include non-conductive paste.

In some examples, spaces between end portions of the interposer substrate **200** and end portions of the lower mold layer **130** may be expanded or extended since the second extension trenches **T2** are formed, and thus the underfill resin solution may be easily injected into the space between the interposer substrate **200** and the lower mold layer **130**. In addition, the widths of the upper portions of the through-holes **131** may in effect be increased by the first and second extension trenches **T1** and **T2**, and thus the underfill resin solution may be easily injected into the through-holes **131**. On the other hand, the second extension trenches **T2** may function as dams to prevent the underfill resin solution from overflowing onto sidewalls and/or a top surface of the interposer substrate **200**.

Referring to FIG. **8D**, external terminals **150** may be formed on a bottom surface of the lower substrate **101**. The external terminals **150** may be formed by a soldering process. The external terminals **150** may include, for example, solder balls.

A cutting process may be performed along the scribing region **SR** of the lower substrate **101** to cut the lower substrate **101** and the lower mold layer **130**. Thus, packaged semiconductor devices including unit lower packages, on which the interposer substrates **200** are stacked, respectively, may be separated from each other. At this stage, each packaged semiconductor device may be considered its own semiconductor package.

Referring again to FIGS. 2A and 2B, an upper package 600 may be stacked on the interposer substrate 200. The upper package 600 may include an upper substrate 601, upper semiconductor chips 610 mounted on the upper substrate 601, bonding wires 620 electrically connecting the upper semiconductor chips 610 to the upper substrate 601, and an upper mold layer 630 covering the upper semiconductor chips 610. Upper connection terminals 500 may be formed between the upper package 600 and the interposer substrate 200. The upper connection terminals 500 may include, for example, solder balls. Thus, a semiconductor package in the form of a package-on-package (PoP), for example, is completed.

FIGS. 9A to 9C are cross-sectional views illustrating a method of manufacture according to some examples of the inventive concepts. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators, and the descriptions thereto will be omitted for the sake of brevity.

Referring to FIG. 9A, an interposer substrate 200 may be prepared. The interposer substrate 200 may include insulating layers, metal interconnection lines, and second terminals 220. The second terminals 220 may adhere to a bottom surface of the interposer substrate 200. The interposer substrate 200 may include unit substrate regions USR and a scribing region SR'. The scribing region SR' may be disposed between the unit substrate regions USR. For example, each of the unit substrate regions USR may be surrounded by the scribing region SR' when viewed in a plan view.

Referring to FIG. 9B, a lower package 100 may be stacked on each of the unit substrate regions USR of the interposer substrate 200. The lower packages 100 may be spaced apart from each other on the interposer substrate 200. The lower package 100 may include a lower substrate 101, a lower semiconductor chip 110 mounted on a top surface of the lower substrate 101, a lower mold layer 130 covering sidewalls of the lower semiconductor chip 110 and filling a space between the lower substrate 101 and the lower semiconductor chip 110, and first terminals 141 (see FIG. 8B). The lower mold layer 130 may include through-holes 131 exposing the first terminals 141, and first and second extension trenches T1 and T2. The stacking of the lower packages 100 on the interposer substrate 200 may include aligning the first terminals 141 of the lower packages 100 with the second terminals 220 of the interposer substrate 200, and performing a reflow process for unifying the first and second terminals 141 and 220, thereby forming lower connection terminals 300.

An underfill resin layer 400 may be formed in a space between the interposer substrate 200 and each of the lower packages 100. The underfill resin layer 400 may be formed in a space between the lower semiconductor chip 110 and the interposer substrate 200, the first extension trench T1, a space between the lower mold layer 130 and the interposer substrate 200, the through-holes 131, and the second extension trench T2. The underfill resin layer 400 may be formed to surround sidewalls of the lower connection terminals 300.

Referring to FIG. 9C, external terminals 150 may be formed on bottom surfaces of the lower substrates 101. Subsequently, a cutting process may be performed along the scribing region SR' of the interposer substrate 200 to separate the unit substrate regions USR of the interposer substrate 200 from each other. Thus, a unit interposer substrate 200 on which one lower package 100 is stacked may be formed.

Referring again to FIG. 2B, the upper package 600 may be stacked on the interposer substrate 200 with the upper connection terminals 500 interposed therebetween.

FIGS. 10A and 10B are cross-sectional views illustrating a method of manufacture according to some examples of the inventive concepts. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators, and the descriptions thereto will be omitted for the sake of brevity.

Referring to FIG. 10A, after forming the through-holes 131 and the first and second extension trenches T1 and T2 in the lower mold layer 130 in FIG. 8A, an adhesive layer 800 may be formed on the lower mold layer 130. The adhesive layer 800 may be formed on each of the unit package regions UPR of the lower substrate 101. The adhesive layer 800 may be in a liquid or solid state. For example, the adhesive layer 800 may include an adhesive and a flux. The flux may include an oxide-removing agent. In FIG. 10A, the adhesive layer 800 may be formed on the top surface of the lower mold layer 130 and the top surface of the lower semiconductor chip 110. However, examples of the inventive concepts are not limited thereto. In certain examples, the adhesive layer 800 may fill the through-holes 131 and the first and second extension trenches T1 and T2.

Referring to FIG. 10B, interposer substrates 200 may be stacked on the unit package regions UPR of the lower substrate 101, respectively. The stacking of the interposer substrates 200 on the unit package regions UPR of the lower substrate 101 may include aligning the second terminals 220 (see FIG. 8B) of the interposer substrates 200 with the first terminals 141 (see FIG. 8B), and performing a reflow process for unify the first and second terminals 141 and 220, thereby forming lower connection terminals 300. When the second terminals 220 of the interposer substrate 200 are aligned with the first terminals 141, the adhesive layer 800 may fill a space between the lower semiconductor chip 110 and the interposer substrate 200, a space between the lower mold layer 130 and the interposer substrate 200, the regions of the through-holes 131 not occupied by the connection terminals 300, and the first and second extension trenches T1 and T2. The adhesive layer 800 may cover sidewalls of the lower connection terminals 300. Thus the adhesive layer may also serve as a connection-terminal protecting layer. In examples in which the adhesive layer 800 includes the flux agent, the process of providing the flux agent onto the surfaces of the first terminals 141 may be omitted.

Subsequent processes after the reflow process may be substantially the same as described with reference to FIG. 8D, and thus the descriptions thereto are omitted.

FIG. 11 is a cross-sectional view illustrating a method of manufacture according to some examples of the inventive concepts. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators, and the descriptions thereto will be omitted for the sake of brevity.

Referring to FIG. 11, interposer substrates 200 may be stacked on the unit package regions UPR of the lower substrate 101, respectively. The second terminals 220 adhered to the bottom surface of each of the interposer substrates 200 may be aligned with the first terminals 141 disposed on each of the unit package regions UPR. In some examples, a width of the interposer substrate 200 may be greater than a width of the unit package region UPR of the lower substrate 101. For example, outer sidewalls of the interposer substrate 200 may be disposed on the top surface of the lower mold layer 130 disposed on the scribing region

SR of the lower substrate **101**. Thus, in the cutting process of separating the unit lower packages **100**, the interposer substrate **200** and the lower substrate **101** may be cut in such a way that outer sidewalls of the unit package region UPR of the lower substrate **101** are aligned with outer sidewalls of the interposer substrate **200**. In addition, the underfill resin solution (not shown) may overflow onto the top surface of the interposer substrate **200**, and thus portions of the underfill resin layer may be formed on top surfaces of end portions of the interposer substrate **200**. In this case, the end portions of the interposer substrate **200**, which are disposed on the scribing region SR, may be removed by the cutting process. Thus, the portions of the underfill resin layer, which are formed on the end portions of the interposer substrate **200**, may also be removed.

Subsequent processes after the process of stacking the interposer substrates **200** on the lower substrate **101** may be substantially the same as described with reference to FIGS. **8C** and **8D**, and thus the descriptions thereto are omitted.

FIG. **12** is a cross-sectional view illustrating a method of manufacture according to some examples of the inventive concepts. Hereinafter, the same elements as described in the above examples will be indicated by the same reference numerals or the same reference designators, and the descriptions thereto will be omitted for the sake of brevity.

Referring to FIG. **12**, after the reflow process for forming the lower connection terminals **300**, the underfill resin layer **400** may be formed in the space between the interposer substrate **200** and the lower substrate **101**. The interposer substrate **200** may include a through portion **230** formed in a central portion of the interposer substrate **200**. The through portion **230** defines an opening through the interposer substrate **200**. The forming of the underfill resin layer **400** may include locating a nozzle N on the through portion **230** of the interposer substrate **200**, filling the space between the interposer substrate **200** and the lower substrate **101** with an underfill resin solution dispensed from the nozzle N through the opening of the through portion **230**, and hardening (curing) the underfill resin solution. The underfill resin layer **400** may fill the opening defined by the through portion **230** of the interposer substrate **200**. Since the underfill resin solution is injected into the through portion **230** of the interposer substrate **200**, a narrow space between the lower semiconductor chip **110** and the central portion of the interposer substrate **200** may be easily filled with the underfill resin solution.

Although methods of manufacture according to the inventive concepts shown in and described above with reference to FIGS. **8A-8D**, **9A-9C**, **10A** and **10B**, **11** and **12** all include mounting an interposer substrate of the type shown in and described with reference to FIGS. **1-6** to a lower package, it will be readily apparent to those of ordinary skill in the art that the same methods may be applied to examples of the inventive concept shown in and described with reference to FIG. **7** in which an upper package **600** having a substrate **601** is mounted to a lower package. In general, upper packages **600** may be mounted to the lower packages in place of the interposer substrate(s).

According to some examples of the inventive concepts, the underfill resin layer disposed between the lower package and the interposer substrate may surround the sidewalls of the lower connection terminals and may fill the through-holes in which the lower connection terminals are provided. Since the underfill resin layer supports the lower connection terminals, it is possible to prevent cracks from occurring in the lower connection terminals by stress caused between the lower package and the interposer substrate.

While the inventive concepts have been described with reference to example examples, it will be apparent to those skilled in the art that various changes and modifications may be made without departing from the spirits and scopes of the inventive concepts. Therefore, it should be understood that the above examples are not limiting, but illustrative. Thus, the scopes of the inventive concepts are to be determined by the broadest permissible interpretation of the following claims and their equivalents, and shall not be restricted or limited by the foregoing description.

What is claimed is:

1. A semiconductor package comprising:
 - a first substrate;
 - a semiconductor chip disposed on the first substrate;
 - a mold layer covering sides of the semiconductor chip and including a plurality of through-holes;
 - a second substrate disposed on the semiconductor chip and extending over the mold layer;
 - a plurality of connection terminals interposed between the first substrate and the second substrate, the connection terminals being respectively disposed in the through-holes of the mold layer; and
 - an underfill resin layer occupying a region between the semiconductor chip and the second substrate and extending contiguously from said region into the through-holes,
- wherein the plurality of connection terminals and the plurality of through-holes surround the semiconductor chip when viewed in a plan view,
- wherein the mold layer has therein a first trench extending contiguously around the semiconductor chip and interposed between the semiconductor chip and the plurality of connection terminals when viewed in a plan view,
- wherein the first trench opens into the through-holes, and
- wherein a bottom surface of the first trench is located at a level below a top surface of the semiconductor chip, whereby the mold layer is recessed at the first trench relative to the top surface of the semiconductor chip.
2. The semiconductor package of claim **1**, wherein the underfill resin layer fills the first trench.
3. The semiconductor package of claim **1**, wherein a top surface of the mold layer extends between the first trench and the semiconductor chip and is disposed at a level above that of the bottom surface of the first trench, and
- wherein the top surface of the mold layer that extends between the first trench and the semiconductor chip is disposed at substantially the same level as the top surface of the semiconductor chip.
4. The semiconductor package of claim **1**, wherein the bottom surface of the first trench is disposed at a level above that of bottom surfaces of the through-holes.
5. The semiconductor package of claim **1**, wherein the mold layer has a first region disposed between the semiconductor chip and the plurality of connection terminals, a second region disposed to one side of the first region, and a third region disposed between the first region and the second region,
- wherein the plurality of through-holes extend through the third region of the mold layer such that the connection terminals are disposed in the third region, and
- wherein the first trench of the mold layer is disposed in the first region and the mold layer has a second trench disposed in the second region,
- a bottom surface of the second trench being located at a level below the top surface of the semiconductor chip, whereby the mold layer is recessed at the second trench relative to the top surface of the semiconductor chip.

17

6. A semiconductor package comprising:
 a lower package;
 an upper package disposed on the lower package;
 an interposer substrate interposed between the lower package and the upper package, the interposer substrate including a layer of electrically conductive wiring;
 an underfill resin layer occupying a region between the lower package and the interposer substrate; and
 a connection terminal disposed between the lower package and the interposer substrate, wherein the lower package comprises:
 a substrate;
 a semiconductor chip disposed on the substrate; and
 a mold layer covering sides of the semiconductor chip and including a through-hole,
 wherein the connection terminal is disposed in the through-hole and electrically connects the lower package to the interposer substrate, and
 wherein the connection terminal occupies a portion of the through-hole and the underfill resin layer fills a region of the through-hole that is not occupied by the connection terminal,
 wherein the interposer substrate has a downwardly facing bottom surface,
 wherein the interposer substrate includes protrusions protruding from the bottom surface thereof or the semiconductor package further includes support patterns in contact with the bottom surface of the interposer substrate, and
 wherein the protrusions or the support patterns extend through the underfill resin layer to a top surface of the semiconductor chip so as to contact the top surface of the semiconductor chip.
7. The semiconductor package of claim 6, wherein the underfill resin layer covers a circumferential surface of the connection terminal within the through-hole.
8. The semiconductor package of claim 6, wherein the mold layer has therein a first trench situated between the semiconductor chip and the connection terminal and a bottom surface of the first trench is located at a level below the top surface of the semiconductor chip, whereby the mold layer is recessed at the first trench relative to the top surface of the semiconductor chip, and
 wherein the first trench opens into the through-hole.
9. The semiconductor package of claim 8, wherein the underfill resin layer fills the first trench.
10. The semiconductor package of claim 8, wherein the bottom surface of the first trench is disposed at a level above that of a bottom surface of the through-hole.
11. The semiconductor package of claim 8, wherein a top surface of the mold layer extends between the first trench and the semiconductor chip and is disposed at a level above that of the bottom surface of the first trench, and
 wherein the top surface of the mold layer that extends between the first trench and the semiconductor chip is disposed at substantially the same level as the top surface of the semiconductor chip.
12. The semiconductor package of claim 7, wherein the underfill resin layer contacts a top surface of the semiconductor chip and the bottom surface of the interposer substrate.
13. A semiconductor package comprising:
 a first package substrate including a first insulating layer and a first layer of electrically conductive wiring;
 a first semiconductor chip disposed on and electrically connected to the first package substrate;

18

- a mold layer covering sides of the first semiconductor chip and including a plurality of through-holes;
 a second substrate disposed on the first semiconductor chip and extending over the mold layer, the second substrate including a second insulating layer and a second layer of electrically conductive wiring;
 a second semiconductor chip disposed on and electrically connected to the second substrate;
 a plurality of connection terminals that electrically connect the first package substrate to the second substrate, the connection terminals being respectively disposed in the through-holes of the mold layer; and
 a connection terminal-protecting layer occupying a region between the first semiconductor chip and the second substrate and extending contiguously from said region into the through-holes,
 wherein the plurality of connection terminals and the plurality of through-holes surround the first semiconductor chip when viewed in a plan view,
 wherein each of the connection terminals occupies a portion of a respective one of the through-holes in which it is disposed,
 wherein the connection terminal-protecting layer fills regions of the through-holes that are not occupied by the connection terminals,
 wherein the mold layer has therein a first trench situated between the first semiconductor chip and the plurality of connection terminals and opening into the through-holes,
 wherein a bottom surface of the first trench is located at a level below a top surface of the first semiconductor chip, whereby the mold layer is recessed at the first trench relative to the top surface of the first semiconductor chip, and
 wherein a lowermost surface of the connection terminal-protecting layer is disposed at a lower level than the bottom surface of the first trench.
14. The semiconductor package of claim 13, wherein the connection terminal-protecting layer fills the first trench, wherein the first trench extending contiguously in a ring around the first semiconductor chip and interposed between the semiconductor chip and the plurality of connection terminals when viewed in a plan view, and wherein the first trench opens into each of respective ones of the through-holes located closest to the first semiconductor chip in the plan view.
15. The semiconductor package of claim 13, wherein the second substrate is an interposer substrate, and the semiconductor package further comprises a second package substrate including a third insulating layer and a third layer of electrically conductive wiring,
 the second semiconductor chip is disposed on and mounted to the second package substrate,
 the interposer substrate is interposed between the second package substrate and the first semiconductor chip and is electrically connected to the second package substrate,
 the interposer substrate has a downwardly facing bottom surface and includes protrusions protruding from the bottom surface, and
 the protrusions extend through the connection terminal-protecting layer to the top surface of the first semiconductor chip so as to contact the top surface of the first semiconductor chip.
16. The semiconductor package of claim 13, further comprising spacers extending from a bottom surface of the second substrate through the connection terminal-protecting

layer and into contact with a top surface of at least one of the first semiconductor chip and the mold layer.

17. The semiconductor package of claim 13, wherein the mold layer has corners along its outermost periphery as viewed in a plan view, and an upwardly facing top surface, 5 the mold layer includes mold support patterns protruding from the top surface of the mold layer, and the mold support patterns are disposed at the corners of the mold layer, respectively.

18. The semiconductor package of claim 13, wherein the 10 second substrate is an interposer substrate, and the semiconductor package further comprises a second package substrate including a third insulating layer and a third layer of electrically conductive wiring,

the second semiconductor chip is disposed on and 15 mounted to the second package substrate,

the interposer substrate is interposed between the second package substrate and the first semiconductor chip and is electrically connected to the second package substrate, 20

the interposer substrate has a through portion defining an opening extending through the interposer substrate, and wherein the connection terminal-protecting layer fills the opening.

* * * * *